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24-Bit $\Delta\Sigma$ ADC with Easy Drive Input Current Cancellation and I²C Interface

FEATURES

- Easy Drive™ Technology Enables Rail-to-Rail Inputs with Zero Differential Input Current
- Directly Digitizes High Impedance Sensors with Full Accuracy
- GND to V_{CC} Input/Reference Common Mode Range
- 2-Wire I²C Interface
- Programmable 50Hz, 60Hz or Simultaneous 50Hz/60Hz Rejection Mode
- 2ppm (0.25LSB) INL, No Missing Codes
- 1ppm Offset and 15ppm Full-Scale Error
- Selectable 2x Speed Mode
- No Latency: Digital Filter Settles in a Single Cycle
- Single Supply 2.7V to 5.5V Operation
- Internal Oscillator
- Six Addresses Available and One Global Address for Synchronization
- Available in a Tiny (3mm × 3mm) 10-Lead DFN Package

APPLICATIONS

- Direct Sensor Digitizer
- Weight Scales
- Direct Temperature Measurement
- Strain Gauge Transducers
- Instrumentation
- Industrial Process Control
- DVMs and Meters

DESCRIPTION

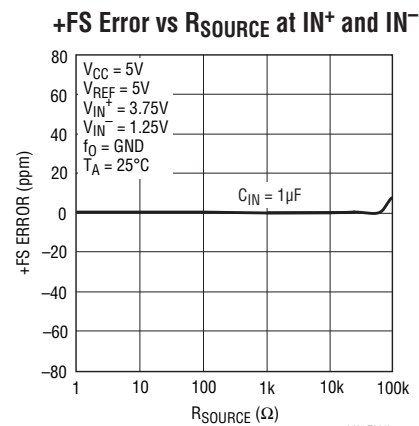
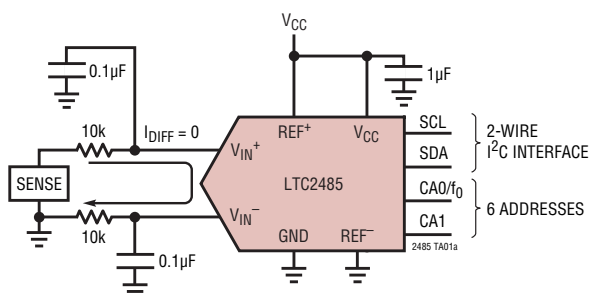
The LTC2485 combines a 24-bit plus sign No Latency $\Delta\Sigma$ ™ analog-to-digital converter with patented Easy Drive technology and I²C digital interface. The patented sampling scheme eliminates dynamic input current errors and the shortcomings of on-chip buffering through automatic cancellation of differential input current. This allows large external source impedances and input signals, with rail-to-rail input range to be directly digitized while maintaining exceptional DC accuracy.

The LTC2485 includes an on-chip oscillator. The LTC2485 can be configured through an I²C interface to reject line frequencies. 50Hz, 60Hz or simultaneous 50Hz/60Hz line frequency rejection can be selected as well as a 2x speed-up mode.

The LTC2485 allows a wide common mode input range (0V to V_{CC}) independent of the reference voltage. The reference can be as low as 100mV or can be tied directly to V_{CC}. The LTC2485 includes an on-chip trimmed oscillator eliminating the need for external crystals or oscillators. Absolute accuracy and low drift are automatically maintained through continuous, transparent, offset and full-scale calibration.

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TYPICAL APPLICATION



2485 TA01b

2485fd

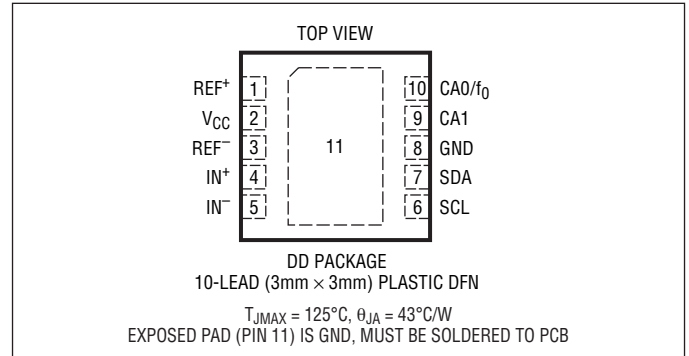
LTC2485

ABSOLUTE MAXIMUM RATINGS

(Notes 1, 2)

Supply Voltage (V_{CC}) to GND	-0.3V to 6V
Analog Input Voltage to GND	-0.3V to ($V_{CC} + 0.3V$)
Reference Input Voltage to GND ..	-0.3V to ($V_{CC} + 0.3V$)
Digital Input Voltage to GND	-0.3V to ($V_{CC} + 0.3V$)
Digital Output Voltage to GND.....	-0.3V to ($V_{CC} + 0.3V$)
Operating Temperature Range	
LTC2485C	0°C to 70°C
LTC2485I	-40°C to 85°C
Storage Temperature Range	-65°C to 125°C

PIN CONFIGURATION



ORDER INFORMATION

LEAD FREE FINISH	TAPE AND REEL	PART MARKING*	PACKAGE DESCRIPTION	TEMPERATURE RANGE
LTC2485CDD#PBF	LTC2485CDD#TRPBF	LBST	10-Lead (3mm x 3mm) Plastic DFN	0°C to 70°C
LTC2485IDD#PBF	LTC2485IDD#TRPBF	LBST	10-Lead (3mm x 3mm) Plastic DFN	-40°C to 85°C

Consult LTC Marketing for parts specified with wider operating temperature ranges. *The temperature grade is identified by a label on the shipping container.

For more information on lead free part marking, go to: <http://www.linear.com/leadfree/>

For more information on tape and reel specifications, go to: <http://www.linear.com/tapeandreel/>

ELECTRICAL CHARACTERISTICS (NORMAL SPEED) The ● denotes the specifications which apply over the full operating temperature range, otherwise specifications are at $T_A = 25^\circ\text{C}$. (Notes 3, 4)

PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
Resolution (No Missing Codes)	$0.1 \leq V_{REF} \leq V_{CC}$, $-FS \leq V_{IN} \leq +FS$ (Note 5)	●	24		Bits
Integral Nonlinearity	$5V \leq V_{CC} \leq 5.5V$, $V_{REF} = 5V$, $V_{IN(CM)} = 2.5V$ (Note 6) $2.7V \leq V_{CC} \leq 5.5V$, $V_{REF} = 2.5V$, $V_{IN(CM)} = 1.25V$ (Note 6)	●	2 1	10	ppm of V_{REF} ppm of V_{REF}
Offset Error	$2.5V \leq V_{REF} \leq V_{CC}$, $GND \leq IN^+ = IN^- \leq V_{CC}$ (Note 13)	●	0.5	2.5	μV
Offset Error Drift	$2.5V \leq V_{REF} \leq V_{CC}$, $GND \leq IN^+ = IN^- \leq V_{CC}$		10		$\text{nV}/^\circ\text{C}$
Positive Full-Scale Error	$2.5V \leq V_{REF} \leq V_{CC}$, $IN^+ = 0.75V_{REF}$, $IN^- = 0.25V_{REF}$	●		25	ppm of V_{REF}
Positive Full-Scale Error Drift	$2.5V \leq V_{REF} \leq V_{CC}$, $IN^+ = 0.75V_{REF}$, $IN^- = 0.25V_{REF}$		0.1		ppm of $V_{REF}/^\circ\text{C}$
Negative Full-Scale Error	$2.5V \leq V_{REF} \leq V_{CC}$, $IN^- = 0.75V_{REF}$, $IN^+ = 0.25V_{REF}$	●		25	ppm of V_{REF}
Negative Full-Scale Error Drift	$2.5V \leq V_{REF} \leq V_{CC}$, $IN^- = 0.75V_{REF}$, $IN^+ = 0.25V_{REF}$		0.1		ppm of $V_{REF}/^\circ\text{C}$
Total Unadjusted Error	$5V \leq V_{CC} \leq 5.5V$, $V_{REF} = 2.5V$, $V_{IN(CM)} = 1.25V$ (Note 6) $5V \leq V_{CC} \leq 5.5V$, $V_{REF} = 5V$, $V_{IN(CM)} = 2.5V$ (Note 6) $2.7V \leq V_{CC} \leq 5.5V$, $V_{REF} = 2.5V$, $V_{IN(CM)} = 1.25V$ (Note 6)		15 15 15		ppm of V_{REF} ppm of V_{REF} ppm of V_{REF}
Output Noise	$5V \leq V_{CC} \leq 5.5V$, $V_{REF} = 5V$, $GND \leq IN^- = IN^+ \leq V_{CC}$ (Note 12)		0.6		μV_{RMS}
Internal PTAT Signal	$T_A = 27^\circ\text{C}$		390	450	mV

2485fd

ELECTRICAL CHARACTERISTICS (2X SPEED)

The ● denotes the specifications which apply over the full operating temperature range, otherwise specifications are at $T_A = 25^\circ\text{C}$. (Notes 3, 4)

PARAMETER	CONDITIONS		MIN	TYP	MAX	UNITS
Resolution (No Missing Codes)	$0.1 \leq V_{REF} \leq V_{CC}$, $-FS \leq V_{IN} \leq +FS$ (Note 5)	●	24			Bits
Integral Nonlinearity	$5V \leq V_{CC} \leq 5.5V$, $V_{REF} = 5V$, $V_{IN(CM)} = 2.5V$ (Note 6) $2.7V \leq V_{CC} \leq 5.5V$, $V_{REF} = 2.5V$, $V_{IN(CM)} = 1.25V$ (Note 6)	●		2 1	10	ppm of V_{REF}
Offset Error	$2.5V \leq V_{REF} \leq V_{CC}$, $GND \leq IN^+ = IN^- \leq V_{CC}$ (Note 13)	●		0.5	2	mV
Offset Error Drift	$2.5V \leq V_{REF} \leq V_{CC}$, $GND \leq IN^+ = IN^- \leq V_{CC}$			100		nV/ $^\circ\text{C}$
Positive Full-Scale Error	$2.5V \leq V_{REF} \leq V_{CC}$, $IN^+ = 0.75V_{REF}$, $IN^- = 0.25V_{REF}$	●			25	ppm of V_{REF}
Positive Full-Scale Error Drift	$2.5V \leq V_{REF} \leq V_{CC}$, $IN^+ = 0.75V_{REF}$, $IN^- = 0.25V_{REF}$			0.1		ppm of $V_{REF}/^\circ\text{C}$
Negative Full-Scale Error	$2.5V \leq V_{REF} \leq V_{CC}$, $IN^- = 0.75V_{REF}$, $IN^+ = 0.25V_{REF}$	●			25	ppm of V_{REF}
Negative Full-Scale Error Drift	$2.5V \leq V_{REF} \leq V_{CC}$, $IN^- = 0.75V_{REF}$, $IN^+ = 0.25V_{REF}$			0.1		ppm of $V_{REF}/^\circ\text{C}$
Output Noise	$5V \leq V_{CC} \leq 5.5V$, $V_{REF} = 5V$, $GND \leq IN^- = IN^+ \leq V_{CC}$			0.84		μV_{RMS}

CONVERTER CHARACTERISTICS

The ● denotes the specifications which apply over the full operating temperature range, otherwise specifications are at $T_A = 25^\circ\text{C}$. (Notes 3, 4)

PARAMETER	CONDITIONS		MIN	TYP	MAX	UNITS
Input Common Mode Rejection DC	$2.5V \leq V_{REF} \leq V_{CC}$, $GND \leq IN^- = IN^+ \leq V_{CC}$ (Note 5)	●	140			dB
Input Common Mode Rejection 50Hz $\pm 2\%$	$2.5V \leq V_{REF} \leq V_{CC}$, $GND \leq IN^- = IN^+ \leq V_{CC}$ (Note 5)	●	140			dB
Input Common Mode Rejection 60Hz $\pm 2\%$	$2.5V \leq V_{REF} \leq V_{CC}$, $GND \leq IN^- = IN^+ \leq V_{CC}$ (Note 5)	●	140			dB
Input Normal Mode Rejection 50Hz $\pm 2\%$	$2.5V \leq V_{REF} \leq V_{CC}$, $GND \leq IN^- = IN^+ \leq V_{CC}$ (Notes 5, 7)	●	110	120		dB
Input Normal Mode Rejection 60Hz $\pm 2\%$	$2.5V \leq V_{REF} \leq V_{CC}$, $GND \leq IN^- = IN^+ \leq V_{CC}$ (Notes 5, 8)	●	110	120		dB
Input Normal Mode Rejection 50Hz/60Hz $\pm 2\%$	$2.5V \leq V_{REF} \leq V_{CC}$, $GND \leq IN^- = IN^+ \leq V_{CC}$ (Notes 5, 9)	●	87			dB
Reference Common Mode Rejection DC	$2.5V \leq V_{REF} \leq V_{CC}$, $GND \leq IN^- = IN^+ \leq V_{CC}$ (Note 5)	●	120	140		dB
Power Supply Rejection DC	$V_{REF} = 2.5V$, $IN^- = IN^+ = GND$			120		dB
Power Supply Rejection, 50Hz $\pm 2\%$	$V_{REF} = 2.5V$, $IN^- = IN^+ = GND$ (Notes 7, 9)			120		dB
Power Supply Rejection, 60Hz $\pm 2\%$	$V_{REF} = 2.5V$, $IN^- = IN^+ = GND$ (Notes 8, 9)			120		dB

ANALOG INPUT AND REFERENCE

The ● denotes the specifications which apply over the full operating temperature range, otherwise specifications are at $T_A = 25^\circ\text{C}$. (Note 3)

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
IN^+	Absolute/Common Mode IN^+ Voltage		$GND - 0.3V$		$V_{CC} + 0.3V$	V
IN^-	Absolute/Common Mode IN^- Voltage		$GND - 0.3V$		$V_{CC} + 0.3V$	V
FS	Full-Scale of the Differential Input ($IN^+ - IN^-$)	●	$0.5V_{REF}$			V
LSB	Least Significant Bit of the Output Code	●	$FS/2^{24}$			
V_{IN}	Input Differential Voltage Range ($IN^+ - IN^-$)	●	-FS		+FS	V
V_{REF}	Reference Voltage Range ($REF^+ - REF^-$)	●	0.1		V_{CC}	V

ANALOG INPUT AND REFERENCE

The ● denotes the specifications which apply over the full operating temperature range, otherwise specifications are at $T_A = 25^\circ\text{C}$. (Note 3)

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS	
C_S (IN ⁺)	IN ⁺ Sampling Capacitance			11		pF	
C_S (IN ⁻)	IN ⁻ Sampling Capacitance			11		pF	
C_S (V _{REF})	V _{REF} Sampling Capacitance			11		pF	
I_{DC_LEAK} (IN ⁺)	IN ⁺ DC Leakage Current	Sleep Mode, IN ⁺ = GND	●	-10	1	10	nA
I_{DC_LEAK} (IN ⁻)	IN ⁻ DC Leakage Current	Sleep Mode, IN ⁻ = GND	●	-10	1	10	nA
I_{DC_LEAK} (V _{REF})	REF ⁺ , REF ⁻ DC Leakage Current	Sleep Mode, V _{REF} = V _{CC}	●	-100	1	100	nA

I²C DIGITAL INPUTS AND DIGITAL OUTPUTS

The ● denotes the specifications which apply over the full operating temperature range, otherwise specifications are at $T_A = 25^\circ\text{C}$. (Note 3)

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
V _{IH}	High Level Input Voltage		●	0.7V _{CC}		V
V _{IL}	Low Level Input Voltage		●		0.3V _{CC}	V
V _{IL} (CA1)	Low Level Input Voltage for Address Pin		●		0.05V _{CC}	V
V _{IH} (CA0/f ₀ ,CA1)	High Level Input Voltage for Address Pins		●	0.95V _{CC}		V
R _{INH}	Resistance from CA0/f ₀ , CA1 to V _{CC} to Set Chip Address Bit to 1		●		10	kΩ
R _{INL}	Resistance from CA1 to GND to Set Chip Address Bit to 0		●		10	kΩ
R _{INF}	Resistance from CA0/f ₀ , CA1 to V _{CC} or GND to Set Chip Address Bit to Float		●	2		MΩ
I _I	Digital Input Current		●	-10	10	μA
V _{HYS}	Hysteresis of Schmitt Trigger Inputs	(Note 5)		0.05V _{CC}		V
V _{OL}	Low Level Output Voltage SDA	I = 3mA	●		0.4	V
t _{OF}	Output Fall Time from V _{IHMIN} to V _{ILMAX}	Bus Load C _B 10pF to 400pF (Note 14)	●	20+0.1C _B	250	ns
t _{SP}	Input Spike Suppression		●		50	ns
I _{IN}	Input Leakage	0.1V _{CC} ≤ V _{IN} ≤ V _{CC}	●		1	μA
C _I	Capacitance for Each I/O Pin		●	10		pF
C _B	Capacitance Load for Each Bus Line		●		400	pF
C _{CAX}	External Capacitive Load On-Chip Address Pins (CA0/f ₀ ,CA1) for Valid Float		●		10	pF
V _{IH} (EXT,OSC)	High Level CA0/f ₀ External Oscillator	2.7V ≤ V _{CC} < 5.5V	●	V _{CC} - 0.5V		V
V _{IL} (EXT,OSC)	Low Level CA0/f ₀ External Oscillator	2.7V ≤ V _{CC} < 5.5V	●		0.5	V

POWER REQUIREMENTS

The ● denotes the specifications which apply over the full operating temperature range, otherwise specifications are at $T_A = 25^\circ\text{C}$. (Note 3)

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
V _{CC}	Supply Voltage		●	2.7	5.5	V
I _{CC}	Supply Current	Conversion Mode (Note 11)	●	160	250	μA
		Sleep Mode (Note 11)	●	1	2	μA

TIMING CHARACTERISTICS

The ● denotes the specifications which apply over the full operating temperature range, otherwise specifications are at $T_A = 25^\circ\text{C}$. (Note 3)

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
f_{EOSC}	External Oscillator Frequency Range		● 10		1000	kHz
t_{HEO}	External Oscillator High Period		● 0.125		100	μs
t_{LEO}	External Oscillator Low Period		● 0.125		100	μs
t_{CONV_1}	Conversion Time for 1x Speed Mode	50Hz Mode	● 157.2	160.3	163.5	ms
		60Hz Mode	● 131.0	133.6	136.3	ms
		Simultaneous 50Hz/60Hz Mode	● 144.1	146.9	149.9	ms
		External Oscillator (Note 10)			41036/ f_{EOSC}	ms
t_{CONV_2}	Conversion Time for 2x Speed Mode	50Hz Mode	● 78.7	80.3	81.9	ms
		60Hz Mode	● 65.6	66.9	68.2	ms
		Simultaneous 50Hz/60Hz Mode	● 72.2	73.6	75.1	ms
		External Oscillator (Note 10)			20556/ f_{EOSC}	ms

I²C TIMING CHARACTERISTICS

The ● denotes the specifications which apply over the full operating temperature range, otherwise specifications are at $T_A = 25^\circ\text{C}$. (Notes 3, 15)

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
f_{SCL}	SCL Clock Frequency		● 0		400	kHz
$t_{\text{HD(SDA)}}$	Hold Time (Repeated) START Condition		● 0.6			μs
t_{LOW}	LOW Period of the SCL Clock Pin		● 1.3			μs
t_{HIGH}	HIGH Period of the SCL Clock Pin		● 0.6			μs
$t_{\text{SU(STA)}}$	Set-Up Time for a Repeated START Condition		● 0.6			μs
$t_{\text{HD(DAT)}}$	Data Hold Time		● 0		0.9	μs
$t_{\text{SU(DAT)}}$	Data Set-Up Time		● 100			ns
t_r	Rise Time for Both SDA and SCL Signals	(Note 14)	● 20+0.1 C_B		300	ns
t_f	Fall Time for Both SDA and SCL Signals	(Note 14)	● 20+0.1 C_B		300	ns
$t_{\text{SU(STO)}}$	Set-Up Time for STOP Condition		● 0.6			μs

Note 1: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. Exposure to any Absolute Maximum Rating condition for extended periods may affect device reliability and lifetime.

Note 2: All voltage values are with respect to GND.

Note 3: $V_{\text{CC}} = 2.7\text{V}$ to 5.5V unless otherwise specified.

$$V_{\text{REF}} = \text{REF}^+ - \text{REF}^-, V_{\text{REFCM}} = (\text{REF}^+ + \text{REF}^-)/2, \text{FS} = 0.5V_{\text{REF}};$$

$$V_{\text{IN}} = \text{IN}^+ - \text{IN}^-, V_{\text{INCM}} = (\text{IN}^+ + \text{IN}^-)/2.$$

Note 4: Use internal conversion clock or external conversion clock source with $f_{\text{EOSC}} = 307.2\text{kHz}$ unless otherwise specified.

Note 5: Guaranteed by design, not subject to test.

Note 6: Integral nonlinearity is defined as the deviation of a code from a straight line passing through the actual endpoints of the transfer curve. The deviation is measured from the center of the quantization band.

Note 7: 50Hz mode (internal oscillator) or $f_{\text{EOSC}} = 256\text{kHz} \pm 2\%$ (external oscillator).

Note 8: 60Hz mode (internal oscillator) or $f_{\text{EOSC}} = 307.2\text{kHz} \pm 2\%$ (external oscillator).

Note 9: Simultaneous 50Hz/60Hz mode (internal oscillator) or $f_{\text{EOSC}} = 280\text{kHz} \pm 2\%$ (external oscillator).

Note 10: The external oscillator is connected to the CA0/ f_0 pin. The external oscillator frequency, f_{EOSC} , is expressed in kHz.

Note 11: The converter uses the internal oscillator.

Note 12: The output noise includes the contribution of the internal calibration operations.

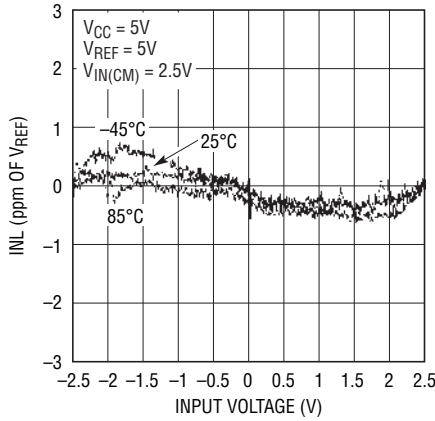
Note 13: Guaranteed by design and test correlation.

Note 14: C_B = capacitance of one bus line in pF.

Note 15: All values refer to $V_{\text{IH(MIN)}}$ and $V_{\text{IL(MAX)}}$ levels.

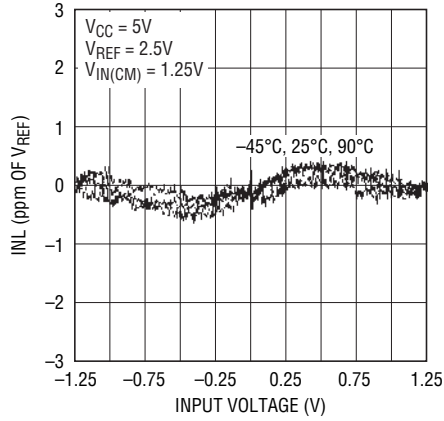
TYPICAL PERFORMANCE CHARACTERISTICS

Integral Nonlinearity
($V_{CC} = 5V$, $V_{REF} = 5V$)



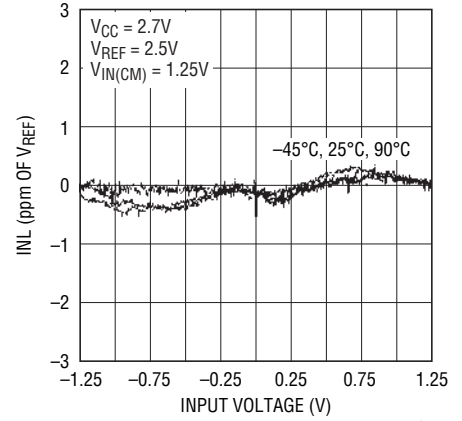
2485 G01

Integral Nonlinearity
($V_{CC} = 5V$, $V_{REF} = 2.5V$)



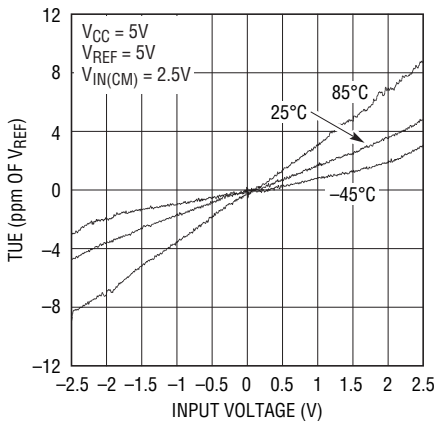
2485 G02

Integral Nonlinearity
($V_{CC} = 2.7V$, $V_{REF} = 2.5V$)



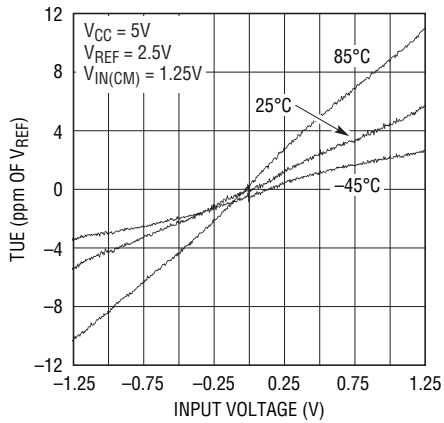
2485 G03

Total Unadjusted Error
($V_{CC} = 5V$, $V_{REF} = 5V$)



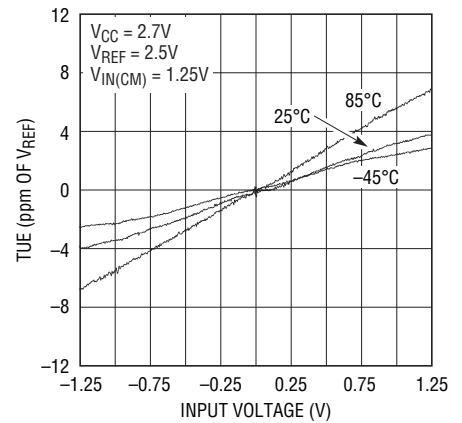
2485 G04

Total Unadjusted Error
($V_{CC} = 5V$, $V_{REF} = 2.5V$)



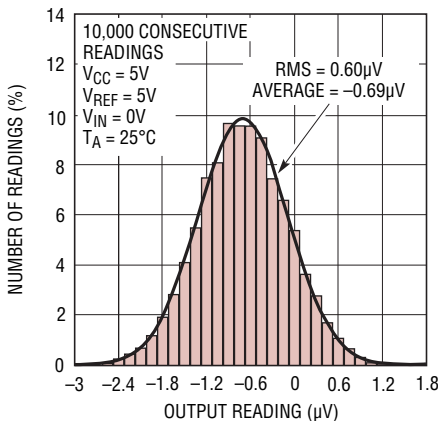
2485 G05

Total Unadjusted Error
($V_{CC} = 2.7V$, $V_{REF} = 2.5V$)



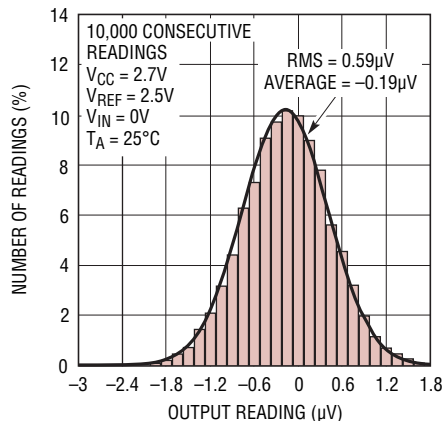
2485 G06

Noise Histogram (6.8sps)



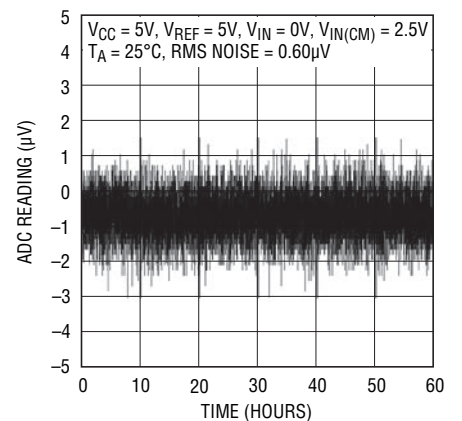
2485 G07

Noise Histogram (7.5sps)



2485 G08

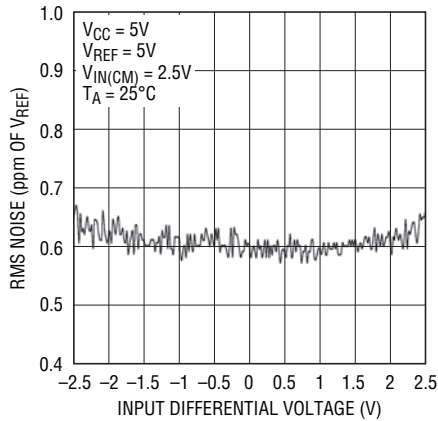
Long-Term ADC Readings



2485 G09

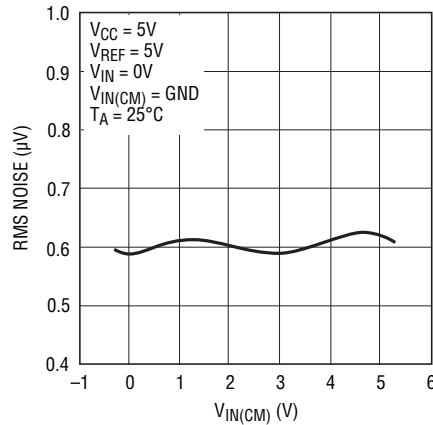
TYPICAL PERFORMANCE CHARACTERISTICS

RMS Noise vs Input Differential Voltage



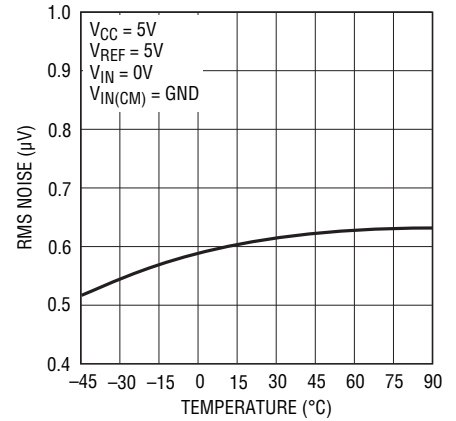
2485 G10

RMS Noise vs $V_{IN(CM)}$



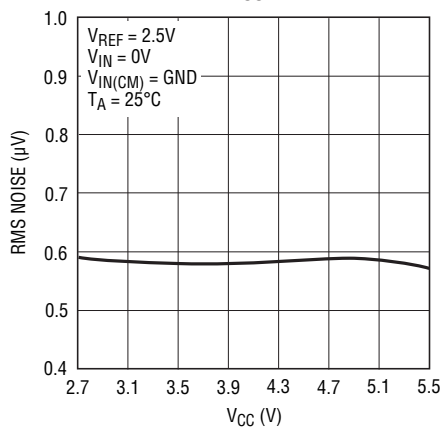
2485 G11

RMS Noise vs Temperature (T_A)



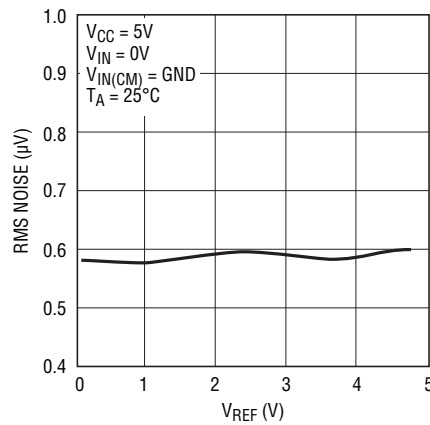
2485 G12

RMS Noise vs V_{CC}



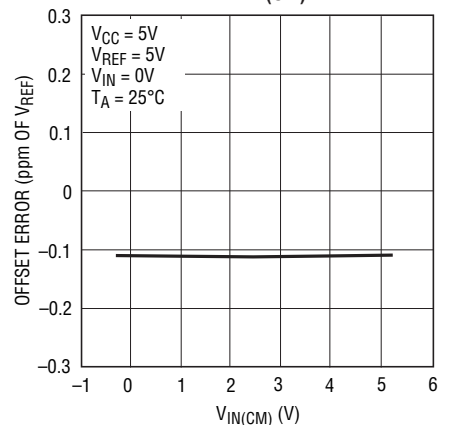
2485 G13

RMS Noise vs V_{REF}



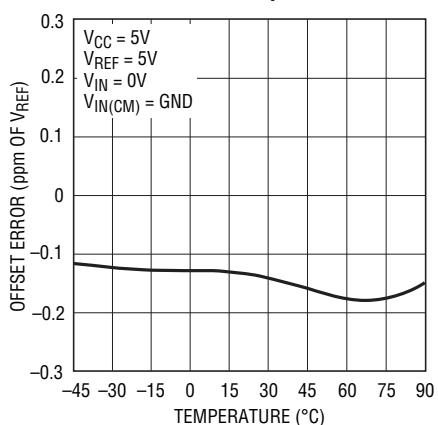
2485 G14

Offset Error vs $V_{IN(CM)}$



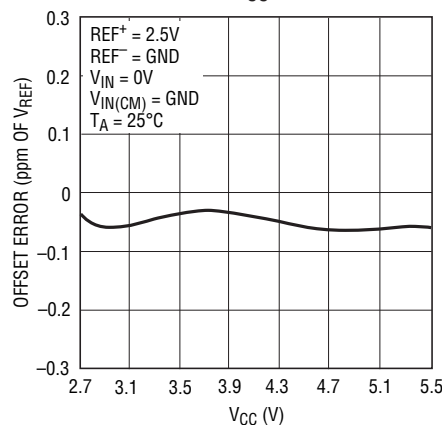
2485 G15

Offset Error vs Temperature



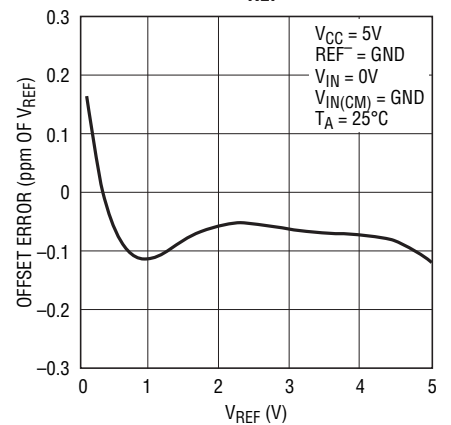
2485 G16

Offset Error vs V_{CC}



2485 G17

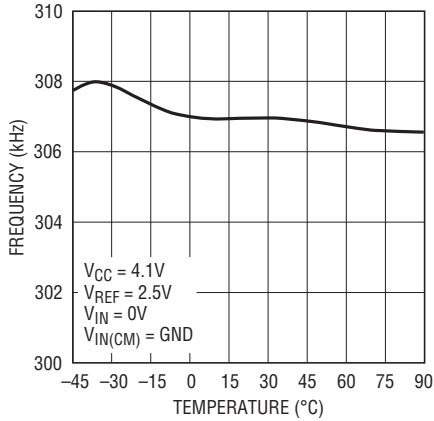
Offset Error vs V_{REF}



2485 G18

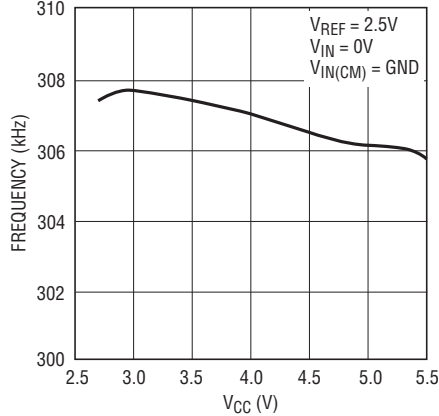
TYPICAL PERFORMANCE CHARACTERISTICS

On-Chip Oscillator Frequency vs Temperature



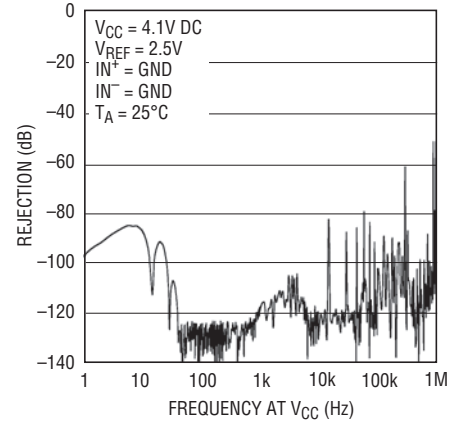
2485 G19

On-Chip Oscillator Frequency vs V_{CC}



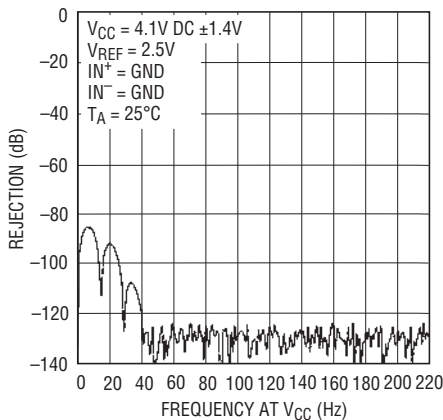
2485 G20

PSRR vs Frequency at V_{CC}



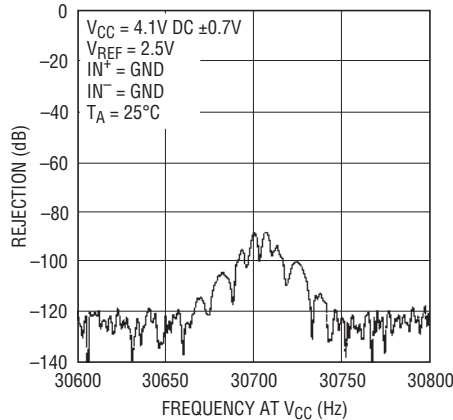
2485 G21

PSRR vs Frequency at V_{CC}



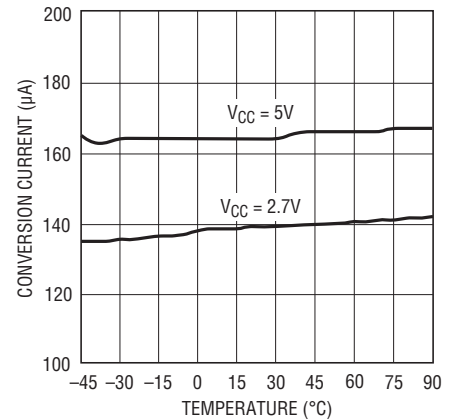
2485 G22

PSRR vs Frequency at V_{CC}



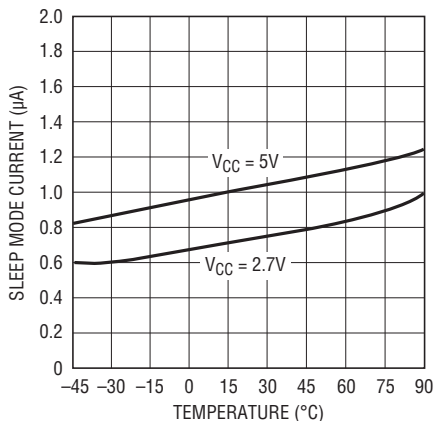
2485 G23

Conversion Current vs Temperature



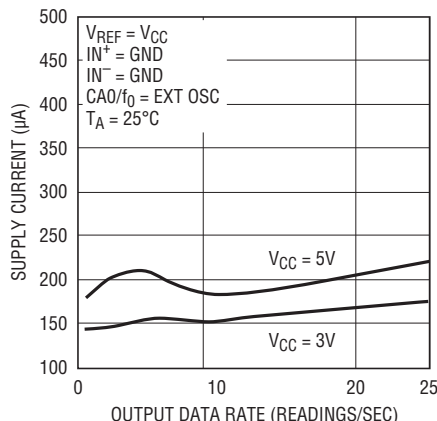
2485 G24

Sleep Mode Current vs Temperature



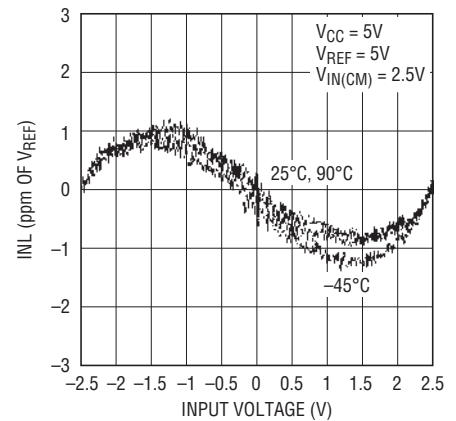
2485 G25

Conversion Current vs Output Data Rate



2485 G26

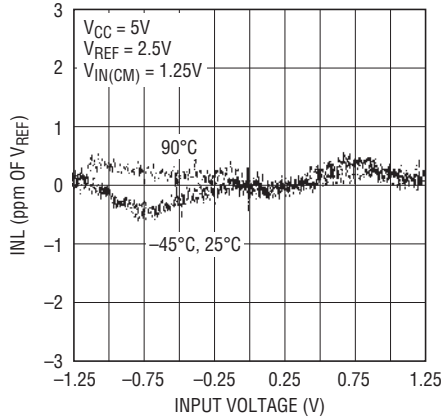
Integral Nonlinearity (2x Speed Mode; V_{CC} = 5V, V_{REF} = 5V)



2485 G27

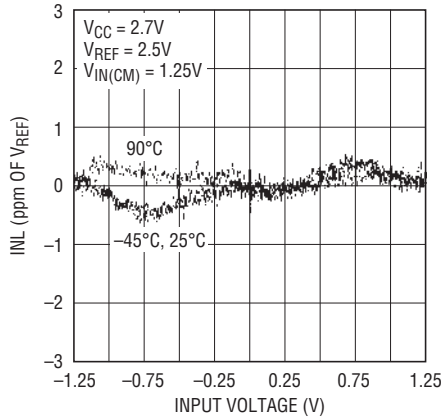
TYPICAL PERFORMANCE CHARACTERISTICS

Integral Nonlinearity (2x Speed Mode; $V_{CC} = 5V$, $V_{REF} = 2.5V$)



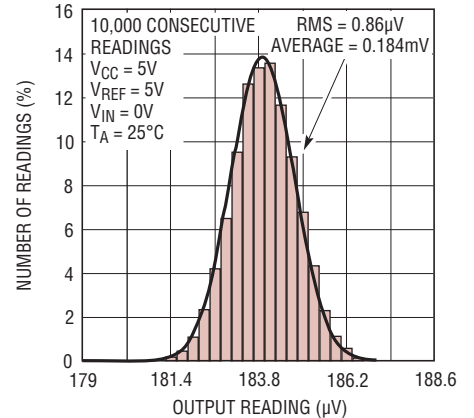
2485 G28

Integral Nonlinearity (2x Speed Mode; $V_{CC} = 2.7V$, $V_{REF} = 2.5V$)



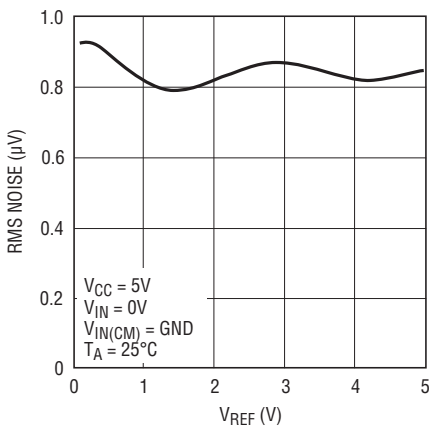
2485 G29

Noise Histogram (2x Speed Mode)



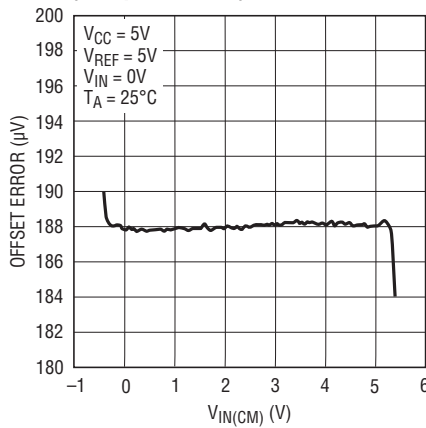
2485 G30

RMS Noise vs V_{REF} (2x Speed Mode)



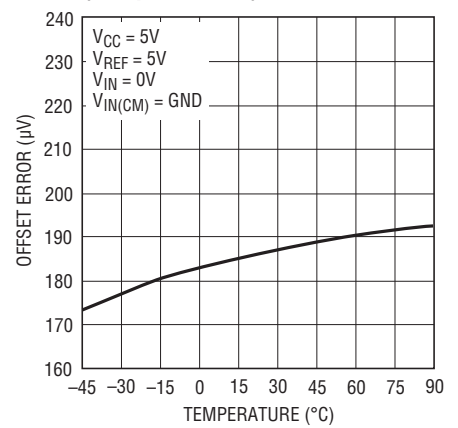
2485 G31

Offset Error vs $V_{IN(CM)}$ (2x Speed Mode)



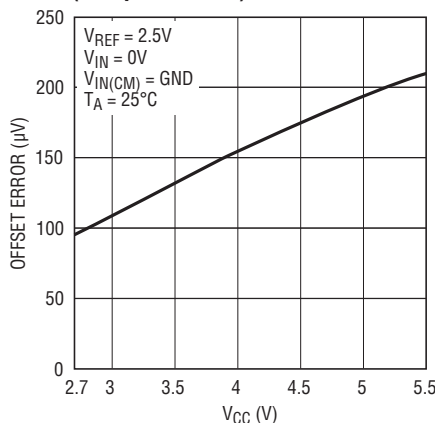
2485 G32

Offset Error vs Temperature (2x Speed Mode)



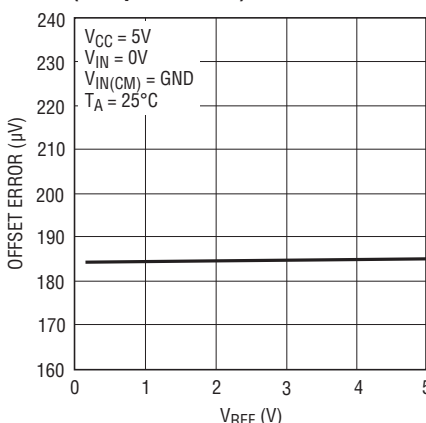
2485 G33

Offset Error vs V_{CC} (2x Speed Mode)



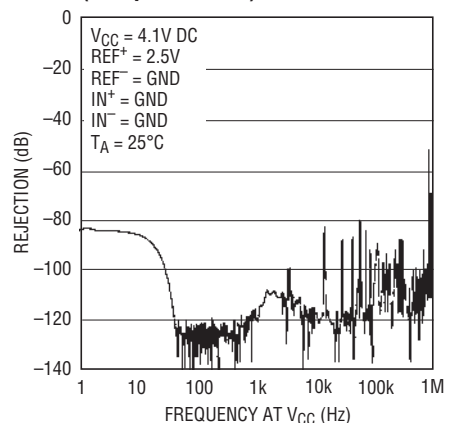
2485 G34

Offset Error vs V_{REF} (2x Speed Mode)



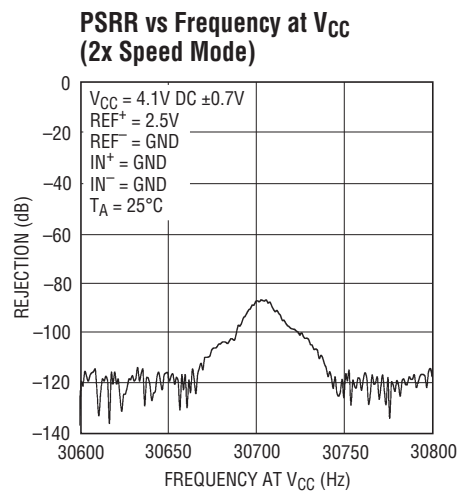
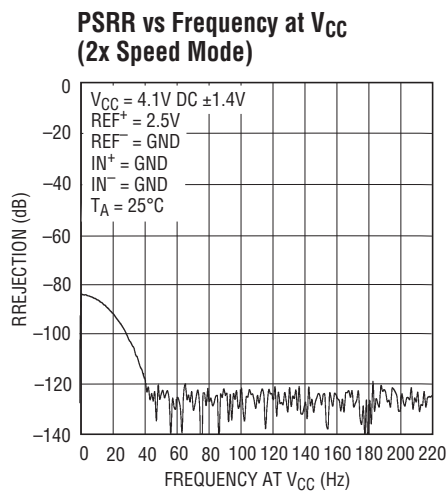
2485 G35

PSRR vs Frequency at V_{CC} (2x Speed Mode)



2485 G36

TYPICAL PERFORMANCE CHARACTERISTICS



PIN FUNCTIONS

REF⁺ (Pin 1), REF⁻ (Pin 3): Differential Reference Input. The voltage on these pins can have any value between GND and V_{CC} as long as the reference positive input, REF⁺, is more positive than the reference negative input, REF⁻, by at least 0.1V.

V_{CC} (Pin 2): Positive Supply Voltage. Bypass to GND (Pin 8) with a 1 μ F tantalum capacitor in parallel with 0.1 μ F ceramic capacitor as close to the part as possible.

IN⁺ (Pin 4), IN⁻ (Pin 5): Differential Analog Input. The voltage on these pins can have any value between GND – 0.3V and $V_{CC} + 0.3V$. Within these limits the converter bipolar input range ($V_{IN} = IN^+ - IN^-$) extends from $-0.5 \cdot V_{REF}$ to $0.5 \cdot V_{REF}$. Outside this input range the converter produces unique overrange and underrange output codes.

SCL (Pin 6): Serial Clock Pin of the I²C Interface. The LTC2485 can only act as a slave and the SCL pin only accepts external serial clock. Data is shifted into the SDA pin on the rising edges of the SCL clock and output through the SDA pin on the falling edges of the SCL clock.

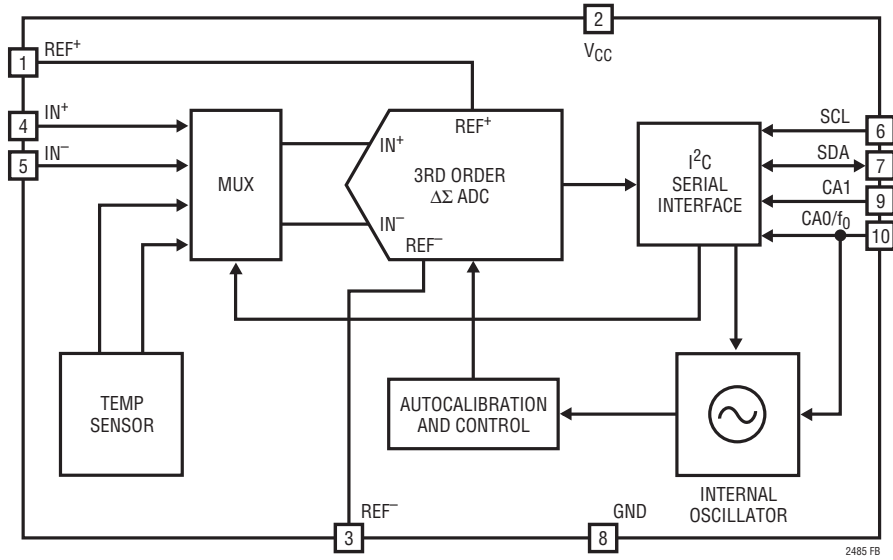
SDA (Pin 7): Bidirectional Serial Data Line of the I²C Interface. In the transmitter mode (Read), the conversion result is output through the SDA pin, while in the receiver mode (Write), the device configuration bits are input through the SDA pin. At data input mode, the pin is high impedance; while at data output mode, it is an open-drain N-channel driver and therefore an external pull-up resistor or current source to V_{CC} is needed.

GND (Pin 8): Ground. Connect this pin to a ground plane through a low impedance connection.

CA1 (Pin 9): Chip Address Control Pin. The CA1 pin is configured as a three state (LOW, HIGH, or Floating) address control bit for the device I²C address.

CA0/f₀ (Pin 10): Chip Address Control Pin/External Clock Input Pin. When no transition is detected on the CA0/f₀ pin, it is a two state (HIGH or Floating) address control bit for the device I²C address. When the pin is driven by an external clock signal with a frequency f_{EOSC} of at least 10kHz, the converter uses this signal as its system clock and the fundamental digital filter rejection null is located at a frequency $f_{EOSC}/5120$ and sets the Chip Address CA0 internally to a HIGH.

FUNCTIONAL BLOCK DIAGRAM



2485 FB

APPLICATIONS INFORMATION

CONVERTER OPERATION

Converter Operation Cycle

The LTC2485 is a low power, $\Delta\Sigma$ analog-to-digital converter with an I²C interface. After power on reset, its operation is made up of three states. The converter operating cycle begins with the conversion, followed by the low power sleep state and ends with the data output/input (see Figure 1).

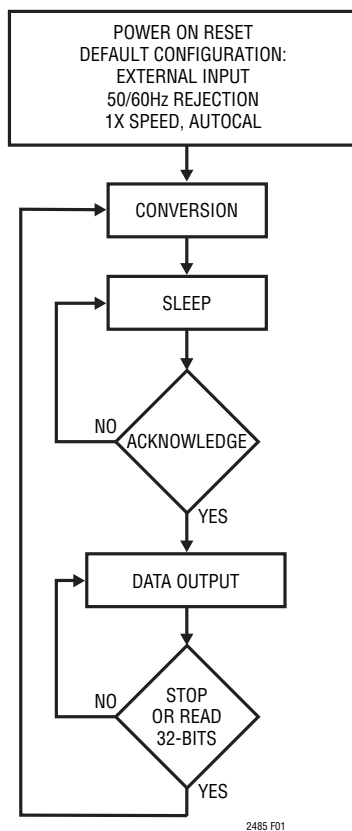


Figure 1. LTC2485 State Transition Diagram

Initially, the LTC2485 performs a conversion. Once the conversion is complete, the device enters the sleep state. While in this sleep state, power consumption is reduced by two orders of magnitude. The part remains in the sleep state as long as it is not addressed for a read/write operation. The conversion result is held indefinitely in a static shift register while the converter is in the sleep state.

The device will not acknowledge an external request during the conversion state. After a conversion is finished,

the device is ready to accept a read/write request. Once the LTC2485 is addressed for a read operation, the device begins outputting the conversion result under control of the serial clock (SCL). There is no latency in the conversion result. The data output is 32 bits long and contains a 24-bit plus sign conversion result. This result is shifted out on the SDA pin under the control of the SCL. Data is updated on the falling edges of SCL allowing the user to reliably latch data on the rising edge of SCL. In write operation, the device accepts one configuration byte and the data is shifted in on the rising edges of the SCL. A new conversion is initiated by a STOP condition following a valid write operation or at the conclusion of a data read operation (read out all 32 bits).

I²C INTERFACE

The LTC2485 communicates through an I²C interface. The I²C interface is a 2-wire open-drain interface supporting multiple devices and masters on a single bus. The connected devices can only pull the bus wires LOW and they never drive the bus HIGH. The bus wires are externally connected to a positive supply voltage via a current-source or pull-up resistor. When the bus is free, both lines are HIGH. Data on the I²C-bus can be transferred at rates of up to 100kbit/s in the Standard-mode and up to 400kbit/s in the Fast-mode. The V_{CC} power should not be removed from the device when the I²C bus is active to avoid loading the I²C bus lines through the internal ESD protection diodes.

Each device on the I²C bus is recognized by a unique address stored in that device and can operate as either a transmitter or receiver, depending on the function of the device. In addition to transmitters and receivers, devices can also be considered as masters or slaves when performing data transfers. A master is the device which initiates a data transfer on the bus and generates the clock signals to permit that transfer. At the same time any device addressed is considered a slave.

The LTC2485 can only be addressed as a slave. Once addressed, it can receive configuration bits or transmit the last conversion result. Therefore the serial clock line SCL

APPLICATIONS INFORMATION

is an input only and the data line SDA is bidirectional. The device supports the Standard-mode and the Fast-mode for data transfer speeds up to 400kbit/s. Figure 2 shows the definition of timing for Fast/Standard-mode devices on the I²C-bus.

The START and STOP Conditions

A START condition is generated by transitioning SDA from HIGH to LOW while SCL is HIGH. The bus is considered to be busy after the START condition. When the data transfer is finished, a STOP condition is generated by transitioning SDA from LOW to HIGH while SCL is HIGH. The bus is free again a certain time after the STOP condition. START and STOP conditions are always generated by the master.

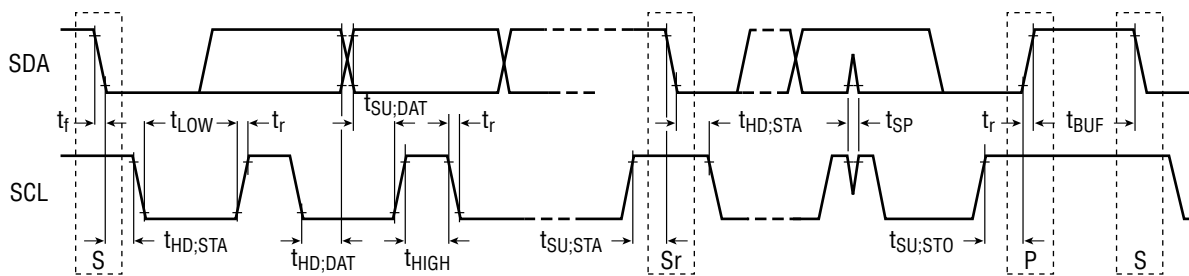
When the bus is in use, it stays busy if a repeated START (Sr) is generated instead of a STOP condition. The repeated START (Sr) conditions are functionally identical to the START (S).

Data Transferring

After the START condition, the I²C bus is busy and data transfer is set between a master and a slave. Data is transferred over I²C in groups of nine bits (one byte) followed by an acknowledge bit, therefore each group takes nine SCL cycles. The transmitter releases the SDA line during the acknowledge clock pulse and the receiver issues an Acknowledge (ACK) by pulling SDA LOW or leaves SDA HIGH to indicate a Not Acknowledge (NAK) condition. Change of data state can only happen while SCL is LOW.

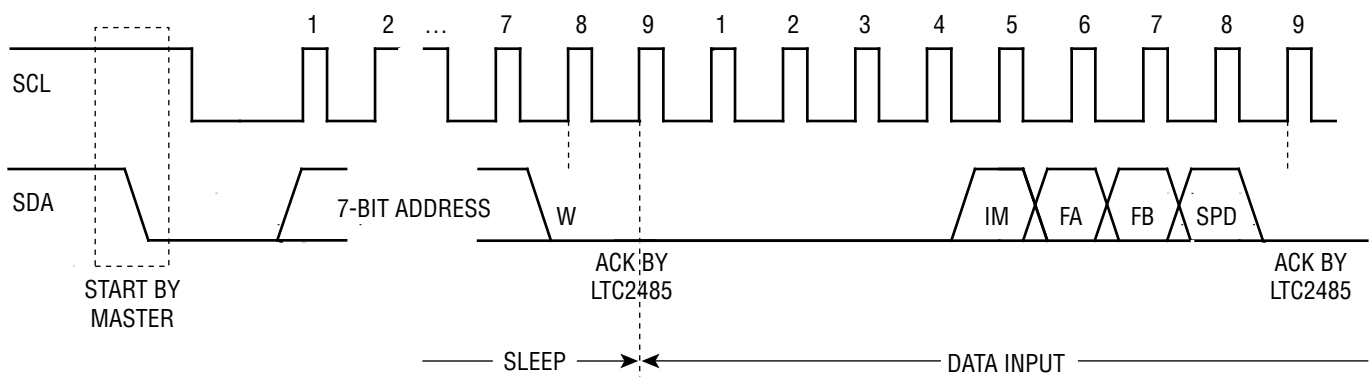
Accessing the Special Features of the LTC2485

The LTC2485 combines a high resolution, low noise $\Delta\Sigma$ analog-to-digital converter with an on-chip selectable temperature sensor, programmable digital filter and output rate control. These special features are selected through a single 8-bit serial input word during the data input/output cycle (see Figure 3).



2485 F02

Figure 2. Definition of Timing for F/S-Mode Devices on the I²C-Bus



2485 F03

Figure 3. Timing Diagram for Writing to the LTC2485

APPLICATIONS INFORMATION

The LTC2485 powers up in a default mode commonly used for most measurements. The device will remain in this mode until a valid write cycle is performed. In this default mode, the measured input is external, the digital filter simultaneously rejects 50Hz and 60Hz line frequency noise, and the speed mode is 1x (offset automatically, continuously calibrated).

The I²C serial interface grants access to any or all special functions contained within the LTC2485. In order to change the mode of operation, a valid write address followed by 8 bits of data are shifted into the device (see Table 1). The first 4 bits are reserved and should be low. The 5th bit (IM) is used to select the internal temperature sensor as the conversion input, while the 6th and 7th bits (FA, FB) combine to determine the line frequency rejection mode. The 8th bit (SPD) is used to double the output rate by disabling the offset auto calibration.

Table 1. Selecting Special Modes

IM	FA	FB	SPD	COMMENTS
0	0	0	0	External Input, 50Hz and 60Hz Rejection, Auto-Calibration
0	0	1	0	External Input, 50Hz Rejection, Auto-Calibration
0	1	0	0	External Input, 60Hz Rejection, Auto-Calibration
0	0	0	1	External Input, 50Hz and 60Hz Rejection, 2x Speed
0	0	1	1	External Input, 50Hz Rejection, 2x Speed
0	1	0	1	External Input, 60Hz Rejection, 2x Speed
1	0	0	0	Temperature Input, 50Hz and 60Hz Rejection, Auto-Calibration
1	0	1	X	Temperature Input, 50Hz Rejection, Auto-Calibration
1	1	0	X	Temperature Input, 60Hz Rejection, Auto-Calibration
X	1	1	X	Reserved, Do Not Use

Temperature Sensor (IM)

The LTC2485 includes an on-chip temperature sensor. The temperature sensor is selected by setting IM = 1 in the serial input data stream. Conversions are performed directly on the temperature sensor by the converter. While operating in this mode, the device behaves as a temperature to bits converter. The digital reading is proportional to the absolute temperature of the device. This feature allows the converter to linearize temperature sensors or continuously remove temperature effects from external sensors. Several applications leveraging this feature are presented in more detail in the applications section. While operating in this mode, the speed is set to normal independent of the control bit (SPD).

Rejection Mode (FA, FB)

The LTC2485 includes a high accuracy on-chip oscillator with no required external components. Coupled with a 4th order digital lowpass filter, the LTC2485 rejects line frequency noise. In the default mode, the LTC2485 simultaneously rejects 50Hz and 60Hz by at least 87dB. The LTC2485 can also be configured to selectively reject 50Hz or 60Hz to better than 110dB.

Speed Mode (SPD)

The LTC2485 continuously performs offset calibrations. Every conversion cycle, two conversions are automatically performed (default) and the results combined. This result is free from offset and drift. In applications where the offset is not critical, the auto-calibration feature can be disabled with the benefit of twice the output rate.

Linearity, full-scale accuracy and full-scale drift are identical for both 2x and 1x speed modes. In both the 1x and 2x speed there is no latency. This enables input steps or multiplexer channel changes to settle in a single conversion cycle easing system overhead and increasing the effective conversion rate.

APPLICATIONS INFORMATION

LTC2485 Data Format

After a START condition, the master sends a 7-bit address followed by a R/W bit. The bit R/W is 1 for a Read request and 0 for a Write request. If the 7-bit address agrees with an LTC2485's address, that device is selected. When the device is in the conversion state, it does not accept the request and issues a Not-Acknowledge (NAK) by leaving SDA HIGH. A write operation will also generate an NAK signal. If the conversion is complete, it issues an acknowledge (ACK) by pulling SDA LOW.

The LTC2485 has two registers. The output register contains the result of the last conversion and a user programmable configuration register that sets the converter operation mode.

The output register contains the last conversion result. After each conversion is completed, the device automatically enters the sleep state where the supply current is reduced to 1 μ A. When the LTC2485 is addressed for a Read operation, it acknowledges (by pulling SDA LOW) and acts as a transmitter. The master and receiver can read up to four bytes from the LTC2485. After a complete Read operation (4 bytes), the output register is emptied, a new conversion is initiated, and a following Read request in the same output phase will be NAKed. The LTC2485 output data stream is 32 bits long, shifted out on the falling edges of SCL. The first bit is the conversion result sign bit (SIG), (see Tables 2 and 3). This bit is HIGH if $V_{IN} \geq 0$.

It is LOW if $V_{IN} < 0$. The second bit is the most significant bit (MSB) of the result. The first two bits (SIG and MSB) can be used to indicate over range conditions. If both bits are HIGH, the differential input voltage is above +FS and the following 24 bits are set to LOW to indicate an over-range condition. If both bits are LOW, the input voltage is below -FS and the following 24 bits are set to HIGH to indicate an underrange condition. The function of these two bits is summarized in Table 1. The next 24 bits contain the conversion results in binary two's complement format. The remaining six bits are Sub LSBs below the 24-bit level.

As long as the voltage on the IN⁺ and IN⁻ pins is maintained within the -0.3V to ($V_{CC} + 0.3V$) absolute maximum operating range, a conversion result is generated for any differential input voltage V_{IN} from $-FS = -0.5 \cdot V_{REF}$ to $+FS = 0.5 \cdot V_{REF}$. For differential input voltages greater than +FS, the conversion result is clamped to the value corresponding to the +FS + 1LSB. For differential input voltages below -FS, the conversion result is clamped to the value corresponding to -FS - 1LSB.

Table 2. LTC2485 Status Bits

INPUT RANGE	BIT 31 SIG	BIT 30 MSB
$V_{IN} \geq 0.5 \cdot V_{REF}$	1	1
$0V \leq V_{IN} < 0.5 \cdot V_{REF}$	1/0	0
$-0.5 \cdot V_{REF} \leq V_{IN} < 0V$	0	1
$V_{IN} < -0.5 \cdot V_{REF}$	0	0

Table 3. LTC2485 Output Data Format

DIFFERENTIAL INPUT VOLTAGE V_{IN}^*	BIT 31 SIG	BIT 30 MSB	BIT 29	BIT 28	BIT 27	...	BIT 0
$V_{IN}^* \geq FS^{**}$	1	1	0	0	0	...	0
$FS^{**} - 1LSB$	1	0	1	1	1	...	1
$0.5 \cdot FS^{**}$	1	0	1	0	0	...	0
$0.5 \cdot FS^{**} - 1LSB$	1	0	0	1	1	...	1
0	1/0***	0	0	0	0	...	0
-1LSB	0	1	1	1	1	...	1
$-0.5 \cdot FS^{**}$	0	1	1	0	0	...	0
$-0.5 \cdot FS^{**} - 1LSB$	0	1	0	1	1	...	1
-FS**	0	1	0	0	0	...	0
$V_{IN}^* < -FS^{**}$	0	0	1	1	1	...	****

* The differential input voltage $V_{IN} = IN^+ - IN^-$.

** The full-scale voltage $FS = 0.5 \cdot V_{ROF}$.

*** The sign bit changes state during the 0 output code when the device is operating in the 2x speed mode.

**** When operating in the 2x speed mode, the underrange output is 0x3FFFxxx.

APPLICATIONS INFORMATION

Initiating a New Conversion

When the LTC2485 finishes a conversion, it automatically enters the sleep state. Once in the sleep state, the device is ready for a Read operation. After the device acknowledges a Read request, the device exits the sleep state and enters the data output state. The data output state concludes and the LTC2485 starts a new conversion once a STOP condition is issued by the master or all 32 bits of data are read out of the device.

During the data read cycle, a stop command may be issued by the master controller in order to start a new conversion and abort the data transfer. This stop command must be issued during the ninth clock cycle of a byte read when the bus is free (the ACK/NAK cycle).

LTC2485 Address

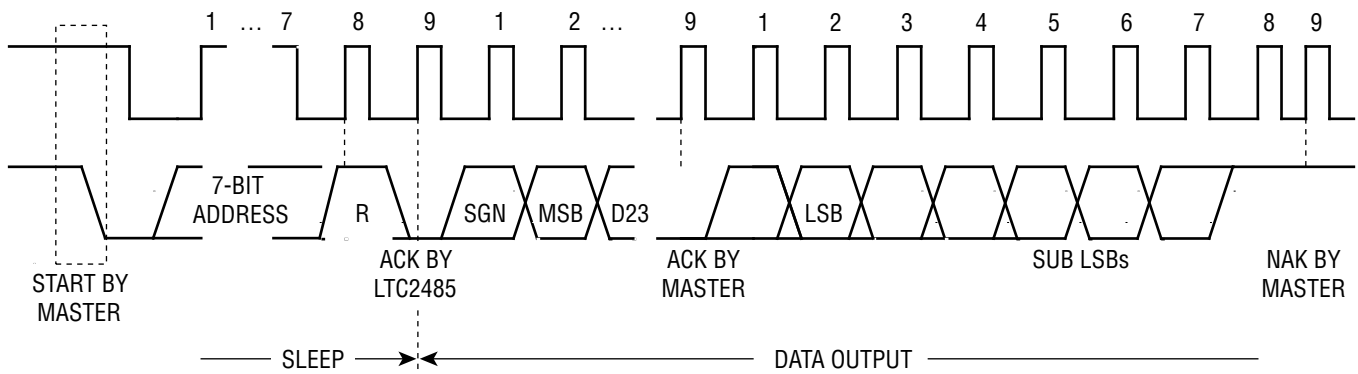
The LTC2485 has two address pins, enabling one in 6 possible addresses, as shown in Table 4.

Table 4. LTC2485 Address Assignment

CA1	CA0/f ₀ *	ADDRESS
LOW	HIGH	001 01 00
LOW	Floating	001 01 01
Floating	HIGH	001 01 11
Floating	Floating	010 01 00
HIGH	HIGH	010 01 10
HIGH	Floating	010 01 11

* CA0/f₀ is treated as HIGH when driven by a valid external clock.

In addition to the configurable addresses listed in Table 4, the LTC2485 also contains a global address (1110111) which may be used for synchronizing multiple LTC2485s.



2485 F04

Figure 4. Timing Diagram for Reading from the LTC2485

APPLICATIONS INFORMATION

OPERATION SEQUENCE

The LTC2485 acts as a transmitter or receiver. The device may be programmed to perform several functions. These include measuring an external differential input signal or an integrated temperature sensor, selecting line frequency rejection (50Hz, 60Hz, or simultaneous 50Hz and 60Hz), and a 2x speed up mode.

Continuous Read

In applications where the configuration does not need to change for each conversion cycle, the conversion result can be continuously read. The configuration remains unchanged from the last value written into the device. If the device has not been written to since power up, the configuration is set to the default value (Input External, simultaneous 50Hz/60Hz rejection, and 1x speed mode). The operation sequence is shown in Figure 6. When the conversion is finished, the device may be addressed for

a read operation. At the end of a read operation, a new conversion begins. At the conclusion of the conversion cycle, the next result may be read using the method described above. If the conversion cycle is not concluded and a valid address selects the device, the LTC2485 generates a NAK signal indicating the conversion cycle is in progress.

Continuous Read/Write

Once the conversion cycle is concluded, the LTC2485 can be written to then read from, using the repeated Start (Sr) command.

Figure 7 shows a cycle which begins with a data Write, a repeated start, followed by a read, and concluded with a stop command. The following conversion begins after all 32 bits are read out of the device or after the STOP command and uses the newly programmed configuration data.

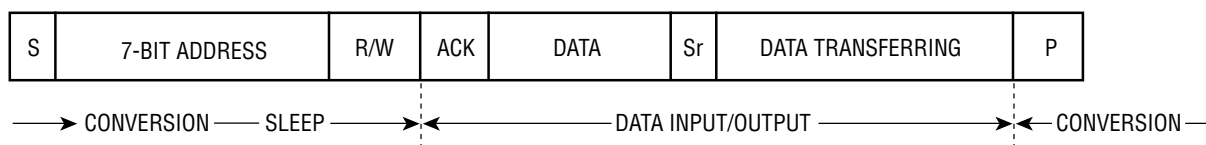


Figure 5. The LTC2485 Conversion Sequence

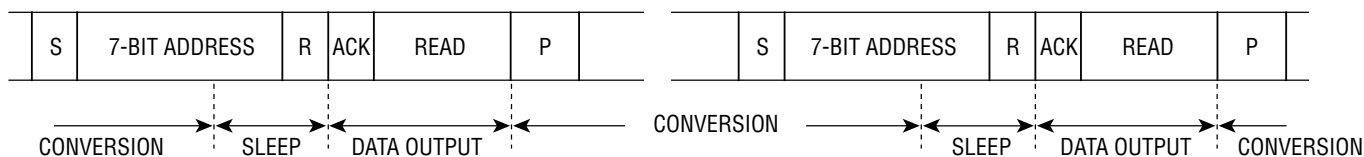


Figure 6. Consecutive Reading at the Same Configuration

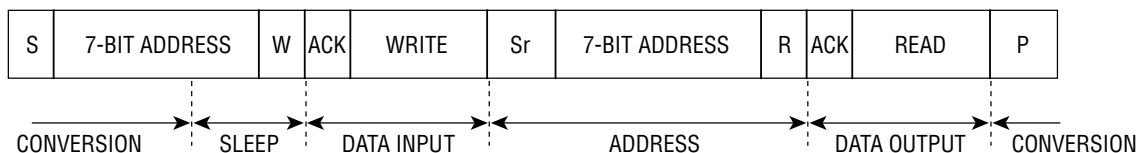


Figure 7. Write, Read, Start Conversion

APPLICATIONS INFORMATION

Discarding a Conversion Result and Initiating a New Conversion with Optional Configuration Updating

At the conclusion of a conversion cycle, a Write cycle can be initiated. Once the Write cycle is acknowledged, a stop (P) command initiates a new conversion. If a new configuration is required, this data can be written into the device and a stop command initiates a new conversion, see Figure 8.

Synchronizing Multiple LTC2485s with the Global Address Call

In applications where several LTC2485s are used on the same I²C bus, all LTC2485s can be synchronized with the global address call. To achieve this, first all the LTC2485s must have completed the conversion cycle. The master issues a Start, followed by the LTC2485 global address 1110111 and a Write request. All LTC2485s will be selected and acknowledge the request. The master then sends the write byte (Optional) and ends the Write operation with a STOP. This will update the configuration registers (if a write byte was sent) and initiate a new conversion simultaneously on all the LTC2485s, as shown in Figure 9. In order to synchronize the start of conversion without affecting the configuration registers, the Write operation can be aborted with a STOP. This initiates a new conversion

on all the LTC2485s without changing the configuration registers.

Easy Drive Input Current Cancellation

The LTC2485 combines a high precision delta-sigma ADC with an automatic differential input current cancellation front end. A proprietary front-end passive sampling network transparently removes the differential input current. This enables external RC networks and high impedance sensors to directly interface to the LTC2485 without external amplifiers. The remaining common mode input current is eliminated by either balancing the differential input impedances or setting the common mode input equal to the common mode reference (see Automatic Input Current Cancellation section). This unique architecture does not require on-chip buffers enabling input signals to swing all the way to ground and up to V_{CC}. Furthermore, the cancellation does not interfere with the transparent offset and full-scale auto-calibration and the absolute accuracy (full-scale + offset + linearity) is maintained even with external RC networks.

Conversion Clock

A major advantage the delta-sigma converter offers over conventional type converters is an on-chip digital filter

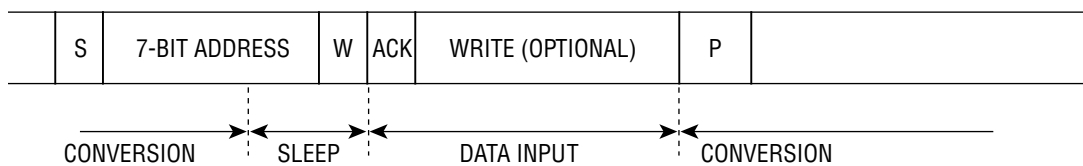


Figure 8. Start a New Conversion without Reading Old Conversion Result

2485 F08

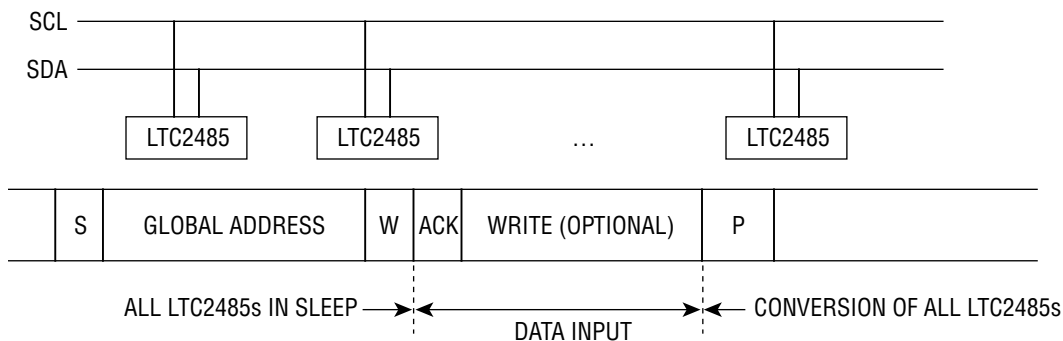


Figure 9. Synchronize the LTC2485s with the Global Address Call

2485 F09

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(commonly implemented as a SINC or Comb filter). For high resolution, low frequency applications, this filter is typically designed to reject line frequencies of 50Hz or 60Hz plus their harmonics. The filter rejection performance is directly related to the accuracy of the converter system clock. The LTC2485 incorporates a highly accurate on-chip oscillator. This eliminates the need for external frequency setting components such as crystals or oscillators.

Frequency Rejection Selection (CA0/f₀)

The LTC2485 internal oscillator provides better than 110dB normal mode rejection at the line frequency and all its harmonics (up to the 255th) for 50Hz \pm 2% or 60Hz \pm 2%, or better than 87dB normal mode rejection from 48Hz to 62.4Hz. The rejection mode is selected by writing to the on-chip configuration register (the default mode at power-up is simultaneous 50Hz/60Hz rejection).

When a fundamental rejection frequency different from 50Hz or 60Hz is required or when the converter must be synchronized with an outside source, the LTC2485 can operate with an external conversion clock. The converter automatically detects the presence of an external clock signal at the CA0/f₀ pin and turns off the internal oscillator. The chip address for CA0 is internally set HIGH. The frequency f_{EOSC} of the external signal must be at least 10kHz to be detected. The external clock signal duty cycle is not significant as long as the minimum and maximum specifications for the high and low periods t_{HE0} and t_{LE0} are observed.

While operating with an external conversion clock of a frequency f_{EOSC}, the LTC2485 provides better than 110dB normal mode rejection in a frequency range of f_{EOSC}/5120

\pm 4% and its harmonics. The normal mode rejection as a function of the input frequency deviation from f_{EOSC}/5120 is shown in Figure 10.

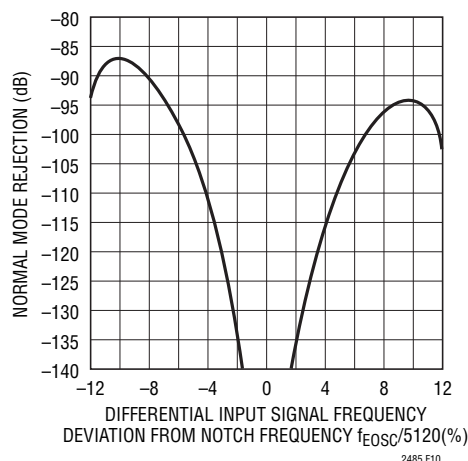


Figure 10. LTC2485 Normal Mode Rejection When Using an External Oscillator

Whenever an external clock is not present at the CA0/f₀ pin, the converter automatically activates its internal oscillator and enters the Internal Conversion Clock mode. CA0/f₀ may be tied HIGH or left floating in order to set the chip address. The LTC2485 operation will not be disturbed if the change of conversion clock source occurs during the sleep state or during the data output state while the converter uses an external serial clock. If the change occurs during the conversion state, the result of the conversion in progress may be outside specifications but the following conversions will not be affected.

Table 5 summarizes the duration of the conversion state of each state and the achievable output data rate as a function of f_{EOSC}.

Table 5. LTC2485 State Duration

STATE	OPERATING MODE		DURATION
Conversion	Internal Oscillator	60Hz Rejection	133ms, Output Data Rate \leq 7.5 Readings/s for 1x Speed Mode 67ms, Output Data Rate \leq 15 Readings/s for 2x Speed Mode
		50Hz Rejection	160ms, Output Data Rate \leq 6.2 Readings/s for 1x Speed Mode 80ms, Output Data Rate \leq 12.5 Readings/s for 2x Speed Mode
		50Hz/60Hz Rejection	147ms, Output Data Rate \leq 6.8 Readings/s for 1x Speed Mode 73.6ms, Output Data Rate \leq 13.6 Readings/s for 2x Speed Mode
	External Oscillator	CA0/f ₀ = External Oscillator with Frequency f _{EOSC} Hz (f _{EOSC} /5120 Rejection)	41036/f _{EOSC} S, Output Data Rate \leq f _{EOSC} /41036 Readings/s for 1x Speed Mode 20556/f _{EOSC} S, Output Data Rate \leq f _{EOSC} /20556 Readings/s for 2x Speed Mode

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Ease of Use

The LTC2485 data output has no latency, filter settling delay or redundant data associated with the conversion cycle. There is a one-to-one correspondence between the conversion and the output data. Therefore, multiplexing multiple analog voltages is easy.

The LTC2485 performs offset and full-scale calibrations every conversion cycle. This calibration is transparent to the user and has no effect on the cyclic operation described above. The advantage of continuous calibration is extreme stability of offset and full-scale readings with respect to time, supply voltage change and temperature drift.

Power-Up Sequence

The LTC2485 automatically enters an internal reset state when the power supply voltage V_{CC} drops below approximately 2V. This feature guarantees the integrity of the conversion result.

When the V_{CC} voltage rises above this critical threshold, the converter creates an internal power-on-reset (POR) signal with a duration of approximately 4ms. The POR signal clears all internal registers. Following the POR signal, the LTC2485 starts a normal conversion cycle and follows the succession of states described in Figure 1. The first conversion result following POR is accurate within the specifications of the device if the power supply voltage is restored within the operating range (2.7V to 5.5V) before the end of the POR time interval.

On-Chip Temperature Sensor

The LTC2485 contains an on-chip PTAT (proportional to absolute temperature) signal that can be used as a temperature sensor. The internal PTAT has a typical value of 420mV at 27°C and is proportional to the absolute temperature value with a temperature coefficient of $420/(27 + 273) = 1.40\text{mV}/^\circ\text{C}$ (SLOPE), as shown in Figure 11. The internal PTAT signal is used in a single-ended mode referenced to device ground internally. The 1x speed mode with automatic offset calibration is automatically selected for the internal PTAT signal measurement as well.

When using the internal temperature sensor, if the output code is normalized to $R_{SDA} = V_{PTAT}/V_{REF}$, the temperature is calculated using the following formula:

$$T_K = \frac{R_{SDA} \cdot V_{REF}}{\text{SLOPE}} \text{ in Kelvin}$$

and

$$T_C = \frac{R_{SDA} \cdot V_{REF}}{\text{SLOPE}} - 273 \text{ in } ^\circ\text{C}$$

where SLOPE is nominally 1.4mV/°C.

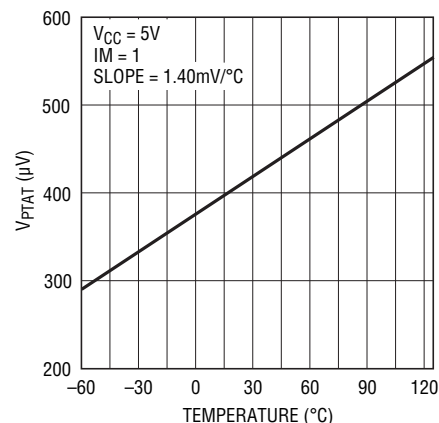
Since the PTAT signal can have an initial value variation which results in errors in SLOPE, to achieve absolute temperature measurements, a one-time calibration is needed to adjust the SLOPE value. The converter output of the PTAT signal, R_{0SDA} , is measured at a known temperature T_0 (in °C) and the SLOPE is calculated as:

$$\text{SLOPE} = \frac{R_{0SDA} \cdot V_{REF}}{T_0 + 273}$$

This calibrated SLOPE can be used to calculate the temperature.

If the same V_{REF} source is used during calibration and temperature measurement, the actual value of the V_{REF} is not needed to measure the temperature as shown in the calculation below:

$$\begin{aligned} T_C &= \frac{R_{SDA} \cdot V_{REF}}{\text{SLOPE}} - 273 \\ &= \frac{R_{SDA}}{R_{0SDA}} \cdot (T_0 + 273) - 273 \end{aligned}$$



2485 F11

Figure 11. Internal PTAT Signal vs Temperature

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Reference Voltage Range

The LTC2485 external reference voltage range is 0.1V to V_{CC} . The converter output noise is determined by the thermal noise of the front-end circuits, and as such, its value in nanovolts is nearly constant with reference voltage. A reduced reference voltage will improve the converter performance when operated with an external conversion clock (external f_0 signal) at substantially higher output data rates (see the Output Data Rate section). V_{REF} must be $\geq 1.1V$ to use the internal temperature sensor.

The reference input is differential. The differential reference input range ($V_{REF} = REF^+ - REF^-$) is 100mV to V_{CC} and the common mode reference input range is 0V to V_{CC} .

Input Voltage Range

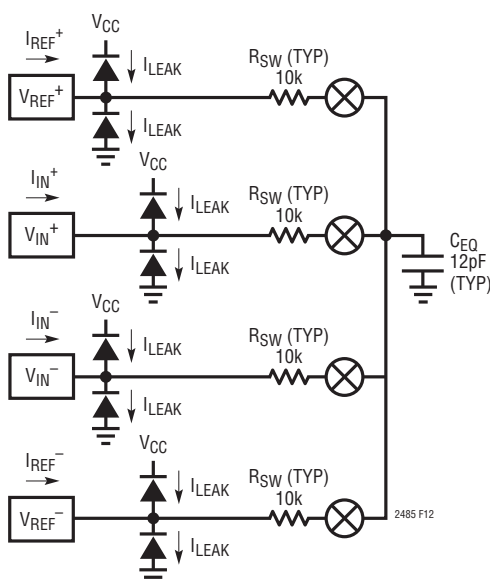
The analog input is truly differential with an absolute/common mode range for the IN^+ and IN^- input pins extending from $GND - 0.3V$ to $V_{CC} + 0.3V$. Outside these limits, the ESD protection devices begin to turn on and the errors due to input leakage current increase rapidly. Within these limits, the LTC2485 converts the bipolar differential input signal, $V_{IN} = IN^+ - IN^-$, from $-FS$ to $+FS$ where $FS = 0.5 \cdot V_{REF}$. Beyond this range, the converter indicates the overrange or the underrange condition using

distinct output codes. Since the differential input current cancellation does not rely on an on-chip buffer, current cancellation and DC performance is maintained rail-to-rail.

Input signals applied to IN^+ and IN^- pins may extend by 300mV below ground and above V_{CC} . In order to limit any fault current, resistors of up to 5k may be added in series with the IN^+ and IN^- pins without affecting the performance of the devices. The effect of the series resistance on the converter accuracy can be evaluated from the curves presented in the Input Current/Reference Current sections. In addition, series resistors will introduce a temperature dependent offset error due to the input leakage current. A 1nA input leakage current will develop a 1ppm offset error on a 5k resistor if $V_{REF} = 5V$. This error has a very strong temperature dependency.

Driving the Input and Reference

The input and reference pins of the LTC2485 converter are directly connected to a network of sampling capacitors. Depending upon the relation between the differential input voltage and the differential reference voltage, these capacitors are switching between these four pins transferring small amounts of charge in the process. A simplified equivalent circuit is shown in Figure 12.



$$I(IN^+)_{AVG} = I(IN^-)_{AVG} = \frac{V_{IN(CM)} - V_{REF(CM)}}{0.5 \cdot R_{EQ}}$$

$$I(REF^+)_{AVG} = \frac{1.5 \cdot V_{REF} - V_{IN(CM)} + V_{REF(CM)}}{0.5 \cdot R_{EQ}} - \frac{V_{IN}^2}{V_{REF} \cdot R_{EQ}} - \frac{0.5 \cdot V_{REF} \cdot D_T}{R_{EQ}} \approx \frac{1.5V_{REF} + (V_{REF(CM)} - V_{IN(CM)})}{0.5 \cdot R_{EQ}} - \frac{V_{IN}^2}{V_{REF} \cdot R_{EQ}}$$

where:

$$V_{REF(CM)} = \left(\frac{REF^+ + REF^-}{2} \right), V_{REF} = REF^+ - REF^-$$

$$V_{IN} = IN^+ - IN^-$$

$$V_{IN(CM)} = \left(\frac{IN^+ + IN^-}{2} \right)$$

$R_{EQ} = 2.71M\Omega$ INTERNAL OSCILLATOR 60Hz MODE

$R_{EQ} = 2.98M\Omega$ INTERNAL OSCILLATOR 50Hz AND 60Hz MODE

$R_{EQ} = (0.833 \cdot 10^{12}) / f_{EOSC}$ EXTERNAL OSCILLATOR

D_T IS THE DENSITY OF A DIGITAL TRANSITION AT THE MODULATOR OUTPUT
WHERE REF^- IS INTERNALLY TIED TO GND

SWITCHING FREQUENCY
 $f_{SW} = 123kHz$ INTERNAL OSCILLATOR
 $f_{SW} = 0.4 \cdot f_{EOSC}$ EXTERNAL OSCILLATOR

Figure 12. LTC2485 Equivalent Analog Input Circuit

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For a simple approximation, the source impedance R_S driving an analog input pin (IN^+ , IN^- , REF^+ or REF^-) can be considered to form, together with R_{SW} and C_{EQ} (see Figure 12), a first order passive network with a time constant $\tau = (R_S + R_{SW}) \cdot C_{EQ}$. The converter is able to sample the input signal with better than 1ppm accuracy if the sampling period is at least 14 times greater than the input circuit time constant τ . The sampling process on the four input analog pins is quasi-independent so each time constant should be considered by itself and, under worst-case circumstances, the errors may add.

When using the internal oscillator, the LTC2485's front-end switched-capacitor network is clocked at 123kHz corresponding to an 8.1 μ s sampling period. Thus, for settling errors of less than 1ppm, the driving source impedance should be chosen such that $\tau \leq 8.1\mu\text{s}/14 = 580\text{ns}$. When an external oscillator of frequency f_{EOSC} is used, the sampling period is $2.5/f_{EOSC}$ and, for a settling error of less than 1ppm, $\tau \leq 0.178/f_{EOSC}$.

Automatic Differential Input Current Cancellation

In applications where the sensor output impedance is low (up to 10k Ω with no external bypass capacitor or up to 500 Ω with 0.001 μ F bypass), complete settling of the input occurs. In this case, no errors are introduced and direct digitization of the sensor is possible.

For many applications, the sensor output impedance combined with external bypass capacitors produces RC time constants much greater than the 580ns required for 1ppm accuracy. For example, a 10k Ω bridge driving a 0.1 μ F bypass capacitor has a time constant an order of magnitude greater than the required maximum. Historically, settling issues were solved using buffers. These buffers led to increased noise, reduced DC performance (Offset/Drift), limited input/output swing (cannot digitize signals near ground or V_{CC}), added system cost and increased power. The LTC2485 uses a proprietary switching algorithm that forces the average differential input current to zero independent of external settling errors. This allows accurate direct digitization of high impedance sensors without the need of buffers (see Figures 13 to 15). Additional errors resulting from mismatched leakage currents must also be taken into account.

The switching algorithm forces the average input current on the positive input (I_{IN^+}) to be equal to the average input current on the negative input (I_{IN^-}). Over the complete conversion cycle, the average differential input current ($I_{IN^+} - I_{IN^-}$) is zero. While the differential input current is zero, the common mode input current $(I_{IN^+} + I_{IN^-})/2$ is proportional to the difference between the common mode input voltage (V_{INCM}) and the common mode reference voltage (V_{REFCM}).

In applications where the input common mode voltage is equal to the reference common mode voltage, as in the case of a balance bridge type application, both the differential and common mode input current are zero. The accuracy of the converter is unaffected by settling errors. Mismatches in source impedances between IN^+ and IN^- also do not affect the accuracy.

In applications where the input common mode voltage is constant but different from the reference common mode voltage, the differential input current remains zero while the common mode input current is proportional to the difference between V_{INCM} and V_{REFCM} . For a reference common mode of 2.5V and an input common mode of 1.5V, the common mode input current is approximately 0.74 μ A (in simultaneous 50Hz/60Hz rejection mode). This common mode input current has no effect on the accuracy if the external source impedances tied to IN^+ and IN^- are matched. Mismatches in these source impedances lead to a fixed offset error but do not affect the linearity or full-scale reading. A 1% mismatch in 1k Ω source resistances leads to a 15ppm shift (74 μ V) in offset voltage.

In applications where the common mode input voltage varies as a function of input signal level (single-ended input, RTDs, half bridges, current sensors, etc.), the common mode input current varies proportionally with input voltage. For the case of balanced input impedances, the common mode input current effects are rejected by the large CMRR of the LTC2485 leading to little degradation in accuracy. Mismatches in source impedances lead to gain errors proportional to the difference between the common mode input voltage and the common mode reference voltage. 1% mismatches in 1k Ω source resistances lead to worst-case gain errors on the order of 15ppm or 1LSB (for 1V differences in reference and input common mode

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voltage). Table 6 summarizes the effects of mismatched source impedance and differences in reference/input common mode voltages.

Table 6. Suggested Input Configuration for LTC2485

	BALANCED INPUT RESISTANCES	UNBALANCED INPUT RESISTANCES
Constant $V_{IN(CM)} - V_{REF(CM)}$	$C_{EXT} > 1nF$ at Both IN^+ and IN^- . Can Take Large Source Resistance with Negligible Error	$C_{EXT} > 1nF$ at Both IN^+ and IN^- . Can Take Large Source Resistance. Unbalanced Resistance Results in an Offset Which Can be Calibrated
Varying $V_{IN(CM)} - V_{REF(CM)}$	$C_{EXT} > 1nF$ at Both IN^+ and IN^- . Can Take Large Source Resistance with Negligible Error	Minimize IN^+ and IN^- Capacitors and Avoid Large Source Impedance (<5k Recommended)

The magnitude of the dynamic input current depends upon the size of the very stable internal sampling capacitors and upon the accuracy of the converter sampling clock. The accuracy of the internal clock over the entire temperature and power supply range is typically better than 0.5%. Such a specification can also be easily achieved by an external clock. When relatively stable resistors (50ppm/°C) are used for the external source impedance seen by IN^+ and IN^- , the expected drift of the dynamic current and offset will be insignificant (about 1% of their respective values over the entire temperature and voltage range). Even for the most stringent applications, a one-time calibration operation may be sufficient.

In addition to the input sampling charge, the input ESD protection diodes have a temperature dependent leakage current. This current, nominally 1nA ($\pm 10nA$ max), results in a small offset shift. A 1k source resistance will create a 1 μV typical and 10 μV maximum offset voltage.

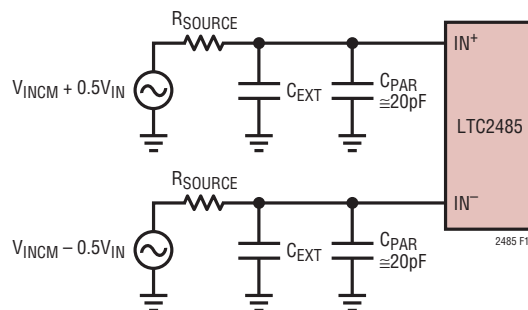


Figure 13. An RC Network at IN^+ and IN^-

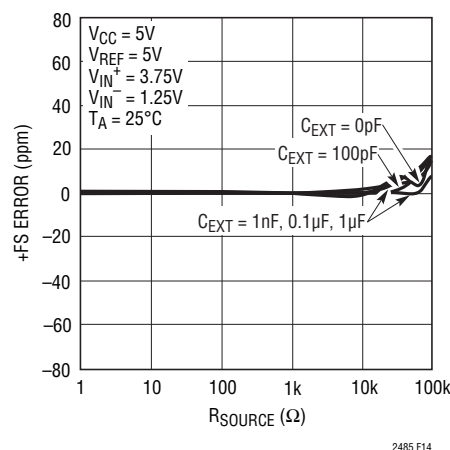


Figure 14. +FS Error vs R_{SOURCE} at IN^+ and IN^-

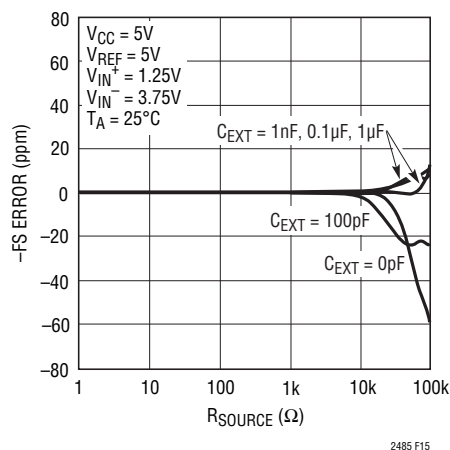


Figure 15. -FS Error vs R_{SOURCE} at IN^+ and IN^-

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Reference Current

In a similar fashion, the LTC2485 samples the differential reference pins REF⁺ and REF⁻ transferring small amount of charge to and from the external driving circuits thus producing a dynamic reference current. This current does not change the converter offset, but it may degrade the gain and INL performance. The effect of this current can be analyzed in two distinct situations.

For relatively small values of the external reference capacitors ($C_{REF} < 1\text{nF}$), the voltage on the sampling capacitor settles almost completely and relatively large values for the source impedance result in only small errors. Such values for C_{REF} will deteriorate the converter offset and gain performance without significant benefits of reference filtering and the user is advised to avoid them.

Larger values of reference capacitors ($C_{REF} > 1\text{nF}$) may be required as reference filters in certain configurations. Such capacitors will average the reference sampling charge and the external source resistance will see a quasi constant reference differential impedance.

In the following discussion, it is assumed the input and reference common mode are the same. Using internal oscillator for 60Hz mode, the typical differential reference resistance is $1\text{M}\Omega$ which generates a full-scale ($V_{REF}/2$) gain error of 0.51ppm for each ohm of source resistance driving the REF⁺ or REF⁻ pins. For 50Hz/60Hz mode, the related difference resistance is $1.1\text{M}\Omega$ and the resulting full-scale error is 0.46ppm for each ohm of source resistance driving the REF⁺ and REF⁻ pins. For 50Hz mode, the related difference resistance is $1.2\text{M}\Omega$ and the resulting full-scale error is 0.42ppm for each ohm of source resistance driving the REF⁺ and REF⁻ pins. When $CA0/f_0$ is driven by an external oscillator with a frequency f_{EOSC} (external conversion clock operation), the typical differential reference resistance is $0.30 \cdot 10^{12}/f_{EOSC} \Omega$ and each ohm of source resistance driving the REF⁺ or REF⁻ pins will result in $1.67 \cdot 10^{-6} \cdot f_{EOSC}$ ppm gain error. The typical +FS and -FS errors for various combinations of source resistance seen by the REF⁺ or REF⁻ pins and external capacitance connected to that pin are shown in Figures 16-19.

In addition to this gain error, the converter INL performance is degraded by the reference source imped-

ance. The INL is caused by the input dependent terms $-V_{IN}^2/(V_{REF} \cdot R_{EQ}) - (0.5 \cdot V_{REF} \cdot D_T)/R_{EQ}$ in the reference pin current as expressed in Figure 12. When using internal oscillator and 60Hz mode, every 100Ω of reference source resistance translates into about 0.67ppm additional INL error. When using internal oscillator and 50Hz/60Hz mode, every 100Ω of reference source resistance translates into about 0.61ppm additional INL error. When using internal oscillator and 50Hz mode, every 100Ω of reference source resistance translates into about 0.56ppm additional INL error. When $CA0/f_0$ is driven by an external oscillator with a frequency f_{EOSC} , every 100Ω of source resistance driving REF⁺ or REF⁻ translates into about $2.18 \cdot 10^{-6} \cdot f_{EOSC}$ ppm additional INL error. Figure 20 shows the typical INL error due to the source resistance driving the REF⁺ or REF⁻ pins when large C_{REF} values are used. The user is advised to minimize the source impedance driving the REF⁺ and REF⁻ pins.

In applications where the reference and input common mode voltages are different, extra errors are introduced. For every 1V of the reference and input common mode voltage difference ($V_{REFCM} - V_{INCM}$) and a 5V reference, each Ohm of reference source resistance introduces an extra $(V_{REFCM} - V_{INCM})/(V_{REF} \cdot R_{EQ})$ full-scale gain error, which is 0.074ppm when using internal oscillator and 60Hz mode. When using internal oscillator and 50Hz/60Hz mode, the extra full-scale gain error is 0.067ppm. When using internal oscillator and 50Hz mode, the extra gain error is 0.061ppm. If an external clock is used, the corresponding extra gain error is $0.24 \cdot 10^{-6} \cdot f_{EOSC}$ ppm.

The magnitude of the dynamic reference current depends upon the size of the very stable internal sampling capacitors and upon the accuracy of the converter sampling clock. The accuracy of the internal clock over the entire temperature and power supply range is typically better than 0.5%. Such a specification can also be easily achieved by an external clock. When relatively stable resistors (50ppm/°C) are used for the external source impedance seen by V_{REF}^+ and V_{REF}^- , the expected drift of the dynamic current gain error will be insignificant (about 1% of its value over the entire temperature and voltage range). Even for the most stringent applications a one-time calibration operation may be sufficient.

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In addition to the reference sampling charge, the reference pins ESD protection diodes have a temperature dependent leakage current. This leakage current, nominally 1nA (± 10 nA max), results in a small gain error. A 100 Ω source resistance will create a 0.05 μ V typical and 0.5 μ V maximum full-scale error.

Output Data Rate

When using its internal oscillator, the LTC2485 produces up to 7.5 samples per second (sps) with a notch frequency of 60Hz, 6.25sps with a notch frequency of 50Hz and 6.82sps with the 50Hz/60Hz rejection mode. The actual output data rate will depend upon the length of the sleep and data output phases which are controlled by the user and which can be made insignificantly short. When oper-

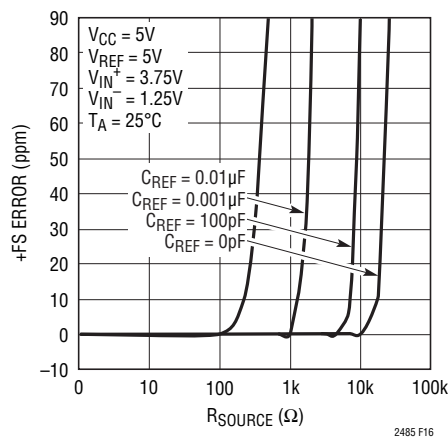


Figure 16. +FS Error vs R_{SOURCE} at REF+ or REF- (Small C_{REF})

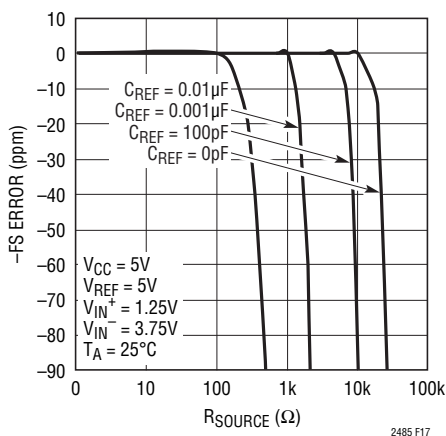


Figure 17. -FS Error vs R_{SOURCE} at REF+ or REF- (Small C_{REF})

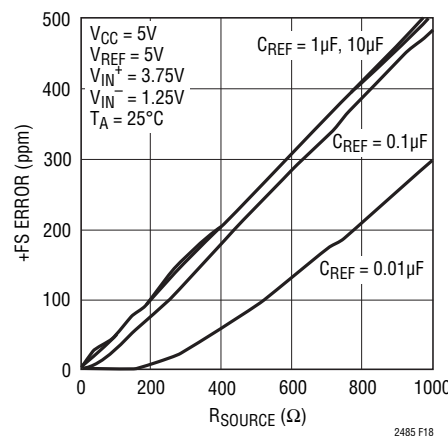


Figure 18. +FS Error vs R_{SOURCE} at REF+ or REF- (Large C_{REF})

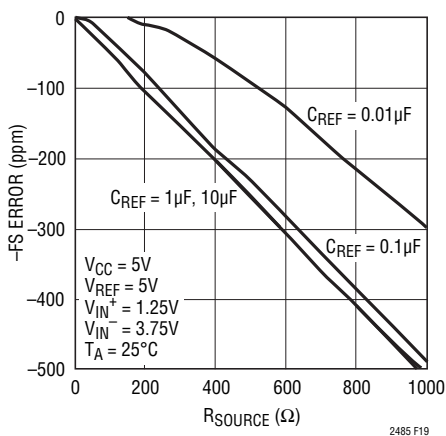


Figure 19. -FS Error vs R_{SOURCE} at REF+ or REF- (Large C_{REF})

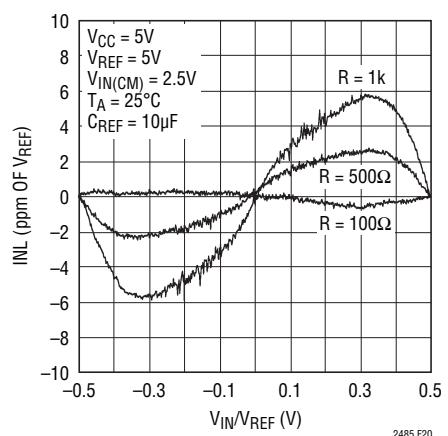


Figure 20. INL vs DIFFERENTIAL Input Voltage and Reference Source Resistance for $C_{REF} > 1\mu F$